

A tool for advanced learning of LFSR-based testing principles

Jutman, Artur; Tšertov, Anton; Ubar, Raimund-Johannes BEC 2006 : 2006 International Baltic Electronics Conference : Tallinn University of Technology, October 2-4, 2006, Tallinn, Estonia : proceedings of the 10th Biennial Baltic Electronics Conference 2006 / p. 175-178 : ill

Aastad, mis möödusid linnulennul

Ubar, Raimund-Johannes Raimund-Johannes Ubar. Bibliograafia 2016 / lk. 13-44 : ill., fot

Abstraction of clock interface for conversion of RTL VHDL to SystemC

Saif Abrar, Syed; Jenihhin, Maksim; Raik, Jaan 2014 IEEE International Advance Computing Conference (IACC) : February 21-22, 2014, Gurgaon, India 2014 / p. 50-55 : ill

Accurate dialysis dose evaluation and extrapolation algorithms during online optical dialysis monitoring

Fridolin, Ivo; Karai, Deniss; Kostin, Sergei; Ubar, Raimund-Johannes IEEE transactions on biomedical engineering 2013 / p. 1371-1377 : ill <https://doi.org/10.1109/TBME.2012.2234458> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Accurate NBTI-induced gate delay modeling based on intensive SPICE simulations

Kostin, Sergei; Raik, Jaan; Ubar, Raimund-Johannes; Jenihhin, Maksim MEDIAN Finale : Workshop on Manufacturable and Dependable Multicore Architectures at Nanoscale : November 10-11, 2015, Tallinn, Estonia 2015 / p. 21-26 : ill

Activity classification for real-time wearable systems : effect of window length, sampling frequency and number of features on classifier performance

Allik, Ardo; Pilt, Kristjan; Karai, Deniss; Fridolin, Ivo; Leier, Mairo; Jervan, Gert 2016 IEEE EMBS Conference on Biomedical Engineering and Sciences (IECBES) : Kuala Lumpur, 4-8 December 2016 2016 / p. 460-464 : ill
<https://doi.org/10.1109/IECBES.2016.7843493>

Address-based data processing over N-ary trees

Sklyarov, Valery; Skliarova, Iuliia; Kruus, Margus; Mihhailov, Dmitri; Sudnitsõn, Aleksander EuroCon 2013 : 01-04 July 2013, Zagreb, Croatia 2013 / p. 1790-1797 : ill

Advanced technical education in the age of cyber physical systems

Vierhaus, Heinrich Theodor; Schölzel, Mario; Raik, Jaan; Ubar, Raimund-Johannes 10th European Workshop on Microelectronics Education : EWME 2014 : May 14-16, 2014, Tallinn, Estonia 2014 / p. 193-198 : ill

Advances in Databases and Information Systems : proceedings of the 9th East-European Conference, ADBIS 2005 : Tallinn, September 12-15, 2005

2005 https://www.ester.ee/record=b2068111*est

Akadeemilisest vabadusest ja riisiterast

Ubar, Raimund-Johannes Tallinna Tehnikaülikooli aastaraamat 2013 2014 / lk. 11-21

An ad-hoc implementation of a remote laboratory

Azad, Siavoosh Payandeh; Kinks, Hannes; Tajammul, Muhammad Adeel; Ellervee, Peeter 2015 International Conference on Microelectronic Systems Education : MSE '15 : Pittsburgh, PA, May 20-21, 2015 2015 / p. 48-51 : ill
<http://dx.doi.org/10.1109/MSE.2015.7160015>

An external test approach for network-on-a-chip switches

Raik, Jaan; Govind, Vineeth; Ubar, Raimund-Johannes ATS '06 : Proceedings of the 15th Asian Test Symposium : November 20-23, 2006, Fukuoka, Japan 2006 / p. 437-442 : ill <http://dx.doi.org/10.1109/ATS.2006.23>

Analysis and comparison of attainable hardware acceleration in all programmable systems-on-chip

Sklyarov, Valery; Skliarova, Iuliia; Silva, João; Sudnitsõn, Aleksander Euromicro Conference on Digital System Design : DSD 2015 : 26-28 August 2015, Funchal, Madeira, Portugal : proceedings 2015 / p. 345-352 : ill <http://dx.doi.org/10.1109/DSD.2015.45>

Applets for learning digital design and test [Electronic resource]

Ubar, Raimund-Johannes; Jutman, Artur; Kruus, Margus; Wuttke, Heinz-Dietrich 1st International Conference on Interactive Mobile and Computer Aided Learning (IMCL2006) : Amman, Jordan, April 19-21, 2006 2006 / p. 1-4 : ill. [CD-ROM]

Application of extensible processing platforms for experiments with FPGA-based circuits

Sklyarov, Valery; Skliarova, Iuliia; Silva, João; Rjabov, Artjom; Sudnitsõn, Aleksander MELECON 2014 : 2014 17th IEEE Mediterranean Electrotechnical Conference : 13-16 April 2014, Beirut, Lebanon 2014 / p. 467-471 : ill
<https://doi.org/10.1109/MELCON.2014.6820579> [Conference proceedings at Scopus](#) [Article at Scopus](#) [Article at WOS](#)

Application of sequential test set compaction to LFSR reseeding

Aleksejev, Igor; Jutman, Artur; Raik, Jaan; Ubar, Raimund-Johannes 26th Norchip Conference : Tallinn, Estonia, 17-18

Applying user domain model to improve Web recommendations

Robal, Tarmo; Kalja, Ahto Databases and information systems VII : selected papers from the tenth International Baltic Conference, DB&IS 2012 2013 / p. 118-131 <https://doi.org/10.3233/978-1-61499-161-8-118> [Conference Proceedings at Scopus](#) [Article at Scopus](#) [Article at WOS](#)

APRICOT : a framework for teaching digital systems verification

Raik, Jaan; Jenihhin, Maksim; Tšepurov, Anton; Reinsalu, Uljana; Ubar, Raimund-Johannes 19th EAAEIE Annual Conference : June 29-July 2, 2008, Tallinn, Estonia : formal proceedings 2008 / p. 172-177 : ill <http://dx.doi.org/10.1109/EAAEIE.2008.4610181>

Arvutipõlvkonnad

Toomsalu, Arvo 2004 http://www.ester.ee/record=b1881924*est

Arvutitehnika riistvara : õpik kõrgkoolidele

Evartson, Teet 2013 https://www.ester.ee/record=b2967116*est

Assessment of diagnostic test for automated bug localization

Tihhomirov, Valentin; Tšepurov, Anton; Jenihhin, Maksim; Raik, Jaan; Ubar, Raimund-Johannes LATW2013 : 14th IEEE Latin-American Test Workshop, Cordoba, Argentina, April 3-5, 2013 : [proceedings] 2013 / [6] p. : ill

Assessment of student's design results in e-learning-scenarios [Electronic resource]

Wuttke, Heinz-Dietrich; Ubar, Raimund-Johannes; Henke, Karsten; Jutman, Artur 8th International Conference on Technology Based Higher Education and Training : 10th to 13th July, 2007, KKR Hotel Kumamoto, Kumamoto, Japan : [proceedings] 2007 / [6] p. [CD-ROM]

Asutajadekaanid : eesmärk on anda inimestele võimalus oma tööd paremini teha

Oorn, Arvo; Jervan, Gert; Kanger, Tõnis; Listra, Enn Mente et Manu 2016 / lk. 18-23 : fot https://artiklid.elnet.ee/record=b2797132*est

Asynchronous fault detection in IEEE P1687 instrument network

Shibin, Konstantin; Devadze, Sergei; Jutman, Artur IEEE 23rd North Atlantic Test Workshop : 14-16 May 2014, Binghampton, New York : proceedings 2014 / p. 73-78 : ill

At-speed functional built-in self-test methodology for processors [Electronic resource]

Ubar, Raimund-Johannes; Indus, Viljar; Kalmend, Oliver Proceedings of the IASTED International Conference on Engineering and Applied Science : December 27-29, 2012, Columbo, Sri Lanka 2012 / p. 168-172 : ill [CD-ROM]

At-speed self-testing of high-performance pipe-lined processing architectures [Electronic resource]

Gorev, Maksim; Ubar, Raimund-Johannes; Ellervee, Peeter; Devadze, Sergei; Raik, Jaan; Min, Mart 31st Norchip Conference : Vilnius, Lithuania, 11-12 November 2013 : conference program and papers 2013 / p. 1-6 : ill [USB]

At-speed testing and test quality evaluation for high-performance pipelined systems Töökiirusel testimine ja testi kvaliteedi hindamine kõrgjõudlus-konveierarhitektuuriga süsteemidele

Gorev, Maksim 2015 <https://digi.lib.ttu.ee//?3953>

At-speed testing of inter-die connections of 3D-SICs in the presence of shore logic

Shibin, Konstantin; Chickermane, Vivek; Keller, Brion; Papamietis, Christos; Marinissen, Erik Jan 2015 Asian Test Symposium : ATS 2015 : 22-25 November 2015, Mumbai, Maharashtra, India : proceedings 2015 / p. 79-84 : ill <https://doi.org/10.1109/ATS.2015.21> [Conference proceedings at Scopus](#) [Article at Scopus](#) [Article at WOS](#)

Aukartus teaduse ees

Ubar, Raimund-Johannes Raimund-Johannes Ubar. Bibliograafia 2016 / lk. 47-56

Aukartus teaduse ees : [essee]. Nikolai Alumäe medal

Ubar, Raimund-Johannes Sirp 2014 / lk. 3-5 : fot <https://www.sirp.ee/s1-artiklid/c21-teadus/aukartus-teaduse-ees/>

Automated design error debug using high-level decision diagrams and mutation operators

Raik, Jaan; Repinski, Urmas; Tšepurov, Anton; Hantson, Hanno; Ubar, Raimund-Johannes; Jenihhin, Maksim Microprocessors and microsystems 2013 / p. 505-513 : ill <https://doi.org/10.1016/j.micpro.2012.11.004> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Automated design error localization in RTL designs

Jenihhin, Maksim; Tšepurov, Anton; Tihhomirov, Valentin; Raik, Jaan; Hantson, Hanno; Ubar, Raimund-Johannes; Bartsch, Günter; Meza Escobar, Jorge Hernan; Wuttke, Heinz-Dietrich IEEE design & test of computers 2014 / p. 83-92 : ill

Automated minimization of concurrent online checkers for network-on-chips

Saltarelli, Pietro; Niazmand, Behrad; Hariharan, Ranganathan; Raik, Jaan; Jervan, Gert; Hollstein, Thomas 10th International Symposium on Reconfigurable and Communication-centric Systems-on-Chip (ReCoSoC 2015) : Bremen, 29 June - 1 July 2015 2015 / [8] p. : ill <http://dx.doi.org/10.1109/ReCoSoC.2015.7238079>

Automatic distribution of local testers for testing distributed systems

Vain, Jüri; Halling, Evelin; Kanter, Gert; Anier, Aivo; Pal, Deepak Databases and information systems IX : selected papers from the twelfth International Baltic Conference, DB&IS 2016 2016 / p. 297-310 : ill <https://doi.org/10.3233/978-1-61499-714-6-297> [Conference Proceedings at Scopus](#) [Article at Scopus](#) [Article at WOS](#)

BASTION - board and SoC test instrumentation for Ageing and No Failure Found

Devadze, Sergei MEDIAN Finale : Workshop on Manufacturable and Dependable Multicore Architectures at Nanoscale : November 10-11, 2015, Tallinn, Estonia 2015 / p. 77

BIST analyzer : a training platform for SoC testing [Electronic resource]

Jutman, Artur; Tšertov, Anton; Tšepurov, Anton; Aleksejev, Igor; Ubar, Raimund-Johannes; Wuttke, Heinz-Dietrich 37th Annual Frontiers in Education Conference : Global Engineering : Knowledge Without Borders, Opportunities Without Passports : Milwaukee, Wisconsin, October 10-13, 2007 2007 / p. S3H-8-S3H-13 : ill. [CD-ROM] <http://dx.doi.org/10.1109/FIE.2007.4418125>

Boolean fault diagnosis with structurally synthesized BDDs

Ubar, Raimund-Johannes Recent progress in the Boolean domain 2014 / p. 303-331 : ill

Bringing research issues into lab scenarios on the example of SoC testing [Electronic resource]

Ubar, Raimund-Johannes; Jutman, Artur; Devadze, Sergei; Wuttke, Heinz-Dietrich International Conference on Engineering Education - ICEE 2007 : September 3-7, 2007, Coimbra, Portugal 2007 / [7] p. : ill. [CD-ROM] <http://icee2007.dei.uc.pt/proceedings/papers/429.pdf>

Clock manipulation for heterogeneous emulation environment

Ellervee, Peeter; Arhipov, Anton; Tammemäe, Kalle Proceedings [of] 24th IEEE Norchip Conference : Linköping, Sweden, 20-21 November 2006 2006 / p. 213-216 : ill <https://ieeexplore.ieee.org/abstract/document/4126984>

CMS drift tubes sector collector relocation phase 1 upgrade [Electronic resource]

Bedoya, C. F.; **Jutman, Artur; Shibin, Konstantin; Devadze, Sergei** 2015 http://cms.cern.ch/iCMS/jsp/openfile.jsp?type=DN&year=2015&files=DN2015_011.pdf

Code compaction within CGRAs

Tajammul, Muhammad Adeel; Jafri, Syed Mohammad Asad Hassan; **Ellervee, Peeter** Proceedings of the 8th Annual Conference of the Estonian National Doctoral School in Information and Communication Technologies : December 5-6, 2014, Rakvere 2014 / p. 133-136 : ill

Code coverage analysis for concurrent programming languages using high-level decision diagrams

Jenihhin, Maksim; Raik, Jaan; Tšepurov, Anton; Reinsalu, Uljana; Ubar, Raimund-Johannes Proceedings of the 12th European Workshop on Dependable Computing : EWDC 2009 : Toulouse, France, May 14-15, 2009 2009 / [4] p. : ill <https://hal.archives-ouvertes.fr/hal-00381559>

Combinational fault simulation in sequential circuits

Ubar, Raimund-Johannes; Kõusaar, Jaak; Gorev, Maksim; Devadze, Sergei 2015 IEEE International Symposium on Circuits and Systems : 24-27 May 2015, Lisboa, Portugal : [proceedings] 2015 / p. 2876-2879 : ill <https://doi.org/10.1109/ISCAS.2015.7169287> [Conference proceedings at Scopus](#) [Article at Scopus](#) [Article at WOS](#)

Combinatorial algorithms of discrete mathematics

Zakrevskij, Arkadij; Pottosin, Yu.; Cheremisinova, L. 2008 http://www.ester.ee/record=b2350865*est

Combining learning, training and research in laboratory course for design and test

Ubar, Raimund-Johannes; Orasson, Elmet; Raik, Jaan; Wuttke, Heinz-Dietrich The 7th Biennial Conference on Electronics and Microsystem Technology "Baltic Electronics Conference" : BEC 2000 : October 8 - 11, 2000, Tallinn, Estonia : conference proceedings 2000 / p. 221-224 : ill https://www.researchgate.net/publication/242397131_Combining_Learning_Training_and_Research_in_Laboratory_Course_for_Design_and_Test

Comparative analysis of sequential circuit test generation approaches

Raik, Jaan; Krivenko, Anna; **Ubar, Raimund-Johannes** BEC 2004 : proceedings of the 9th Biennial Baltic Electronics Conference : October 3-6, 2004, Tallinn, Estonia 2004 / p. 225-228 : ill

Comparison of plan-driven and agile project management approaches : theoretical bases for a case study in Estonian

software industry

Lepmets, Marion; Nael, Margus Databases and Information Systems VI : selected papers from the Ninth International Baltic Conference, DB&IS 2010 2011 / p. 296-308 : ill

Comparison of two approaches to improve functional BIST fault coverage

Kostin, Sergei; Ubar, Raimund-Johannes; Gorev, Maksim; Mägi, Gunnar BEC 2014 : 2014 14th Biennial Baltic Electronics Conference : proceedings of the 14th Biennial Baltic Electronics Conference : Tallinn University of Technology, October 6-8, 2014, Tallinn, Estonia 2014 / p. 105-108 : ill

Complementing ICT studies with learning objects on domain ontologies

Robal, Tarmo; Kruus, Helena; Kalja, Ahto Proceedings of the 24th International Conference on European Association for Education in Electrical and Information Engineering : 30-31 May 2013, Chania, Greece 2013 / p. 92-96 : ill

Complex delay fault reasoning with sequential 7-valued algebra

Kõusaar, Jaak; Ubar, Raimund-Johannes; Aleksejev, Igor 2015 16th Latin American Test Symposium (LATS 2015) : Puerto Vallarta, Mexico, 25-27 March 2015 2015 / [6] p. : ill <http://dx.doi.org/10.1109/LATW.2015.7102403>

Comprehensive abstraction of VHDL RTL cores to ESL SystemC = Register-siirde taseme VHDL kirjelduste kompleksne abstraherimine süsteemitaseme SystemC mudeliteks

Abrar, Syed Saif 2016 http://www.ester.ee/record=b4564850*est

Computing sorted subsets for data processing in communicating software/hardware control systems

Sklyarov, Valery; Skliarova, Iuliia; Rjabov, Artjom; Sudnitsõn, Aleksander International journal of computers communications & control 2016 / p. 126-141 : ill <https://doi.org/10.15837/ijccc.2016.1.1442> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Constraints solving based hierarchical test generation for synchronous sequential circuits = Kitsenduste lahendamisel baseeruv hierarhiline testigeneerimine sünkroonsetele järjestikскеemidele

Viilukas, Taavi 2012 https://www.ester.ee/record=b2888278*est

Construction of the tests of combinational circuit failures by analyzing the orthogonal disjunctive normal forms represented by the alternative graphs

Matrosova, A.Yu.; Pleshkov, A.G.; Ubar, Raimund-Johannes Automation and remote control 2005 / p. 313-327 : ill <https://doi.org/10.1007/s10513-005-0054-9>

Control intensive digital system synthesis

Tammemäe, Kalle 1997 http://www.ester.ee/record=b1060033*est

Critical path tracing based simulation of transition delay faults

Kõusaar, Jaak; Ubar, Raimund-Johannes; Devadze, Sergei; Raik, Jaan Proceedings of the 8th Annual Conference of the Estonian National Doctoral School in Information and Communication Technologies : December 5-6, 2014, Rakvere 2014 / p. 61-66 : ill

Critical path tracing based simulation of transition delay faults

Kõusaar, Jaak; Ubar, Raimund-Johannes; Devadze, Sergei; Raik, Jaan 2014 17th Euromicro Conference on Digital System Design : DSD 2014 : 27-29 August 2014, Verona, Italy : proceedings 2014 / p. 108-113 : ill

Customizable compression architecture for efficient configuration in CGRAs

Jafri, Syed Mohammad Asad Hassan; Ellervee, Peeter 2014 IEEE 22nd International Symposium on Field-Programmable Custom Computing Machines : FCCM 2014 : 11-13 May 2014, Boston, Massachusetts, USA : proceedings 2014 / p. 31 : ill

Customization methodology of a Coarse Grained Reconfigurable Architecture

Azad, Siavoosh Payandeh; Farahini, Nasim; Hemani, Ahmed Norchip : 32nd NORCHIP Conference, 27-28 October 2014, Tampere, Finland 2014 / [4] p. : ill

Data type dependent energy consumption estimation

Ruberg, Priit; Lass, Keijo; Ellervee, Peeter 2nd IEEE NORCAS Conference : 1-2 November 2016, Copenhagen, Denmark 2016 / [5] p. : ill <https://doi.org/10.1109/NORCHIP.2016.7792916>

Databases and Information Systems : proceedings of the 11th International Baltic Conference, Baltic DB&IS 2014 : Tallinn, Estonia, 8-11 June, 2014

2014 http://www.ester.ee/record=b3088507*est

Databases and information systems : proceedings of the Eighth International Baltic Conference, Baltic DB&PIS 2008 : Tallinn, June 2-5, 2008

2008 http://www.ester.ee/record=b2374996*est

Databases and information systems : proceedings of the Fifth International Baltic Conference : Baltic DB & IS 2002 : Tallinn, June 3-6, 2002

2002 http://www.ester.ee/record=b1641978*est

Databases and information systems VIII : selected papers from the Eleventh International Baltic Conference, DB&IS 2014

2014 https://www.ester.ee/record=b4447206*est

Deadlock-free generic routing algorithms for 3-dimensional Networks-on-Chip with reduced vertical link density topologies

Ying, Haoyuan; Jaiswal, Ashok; **Hollstein, Thomas**; Hofmann, Klaus Journal of systems architecture 2013 / p. 528-542 : ill

<https://doi.org/10.1016/j.sysarc.2013.03.005> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Decision diagrams - from a mathematical notion to engineering applications

Stankovic, Radomir S.; **Ubar, Raimund-Johannes**; Astola, Jaakko Facta Universitatis [Niš]. Series electronics and energetics 2011

/ p. 281-301 : ill <http://dx.doi.org/10.2298/FUEE1103281S>

Decision diagrams for diagnostic modeling

Ubar, Raimund-Johannes MEDIAN Finale : Workshop on Manufacturable and Dependable Multicore Architectures at Nanoscale : November 10-11, 2015, Tallinn, Estonia 2015 / p. 43

Defect-oriented BIST quality analysis

Kruus, Helena; Ubar, Raimund-Johannes; Raik, Jaan BEC 2010 : 2010 12th Biennial Baltic Electronics Conference :

proceedings of the 12th Biennial Baltic Electronics Conference : Tallinn University of Technology, October 4-6, 2010, Tallinn, Estonia 2010 / p. 153-156 : ill

Defect-oriented test generation and fault simulation in the environment of MOSCITO

Schneider, Andre; Diener, Karl-Heinz; Gramatova, Elena; Fisherova, Maria; **Ivask, Eero; Ubar, Raimund-Johannes**; Pleskacz, Witold A.; Kuzmicz, W. BEC 2002 : proceedings of the 8th Biennial Baltic Electronics Conference : October 6-9, 2002, Tallinn, Estonia 2002 / p. 303-306 : ill

DefSim - the defective IC

Pleskacz, Witold A.; **Jutman, Artur; Ubar, Raimund-Johannes; Devadze, Sergei** DATE 2007 : Design Automation and Test in Europe : Nice, France, April 16-20, 2007 2007 / p. s96 (2 p.)

Department of Computer Engineering

Keevallik, Andres; Ubar, Raimund-Johannes Research activities / Tallinn Technical University 1993 / p. 75-78

https://www.ester.ee/record=b1053754*est

Dependable embedded systems : FP7 KhAI-ERA project experience

Kharchenko, Vyacheslav; Kulanov, Vitaliy; **Jervan, Gert** 10th European Workshop on Microelectronics Education : EWME 2014 : May 14-16, 2014, Tallinn, Estonia 2014 / p. 26-30 : ill

Design of FPGA-based circuits using hierarchical finite state machines

Skliarova, Iuliia; Sklyarov, Valery; **Sudnitsõn, Aleksander** 2012 http://www.ester.ee/record=b2857138*est

Design space exploration and optimisation for NoC-based timing sensitive systems

Tagel, Mihkel; **Ellervee, Peeter; Jervan, Gert** BEC 2010 : 2010 12th Biennial Baltic Electronics Conference : proceedings of the 12th Biennial Baltic Electronics Conference : Tallinn University of Technology, October 4-6, 2010, Tallinn, Estonia 2010 / p. 177-180 : ill

Design space exploration in multi-level computing systems

Sklyarov, Valery; Skliarova, Iuliia; Silva, João; **Sudnitsõn, Aleksander** CompSysTech'14 : 15th International Conference on Computer Systems and Technologies : Ruse, Bulgaria, June 27-28, 2014 2014 / p. 40-47 : ill <https://doi.org/10.1145/2659532.2659616> [Conference proceedings at Scopus](#) [Article at Scopus](#)

Designing reliable cyber-physical systems : overview associated to the special session at FDL'16

Aleksandrowicz, Gadi; Arbel, Eli; Bloem, Roderick; **Devadze, Sergei; Jenihhin, Maksim; Jutman, Artur; Raik, Jaan; Shibin, Konstantin** The 2016 Forum on Specification & Design Languages : proceedings : Bremen, Germany, September 14-16, 2016 2016 / [8] p. : ill <https://doi.org/10.1109/FDL.2016.7880382>

Developing a data acquisition system for measuring microcontroller energy consumption using LabVIEW

Ruberg, Priit; Lass, Keijo; Ellervee, Peeter BEC 2016 : 2016 15th Biennial Baltic Electronics Conference : proceedings of the 15th Biennial Baltic Electronics Conference : Tallinn University of Technology, October 3-5, 2016, Tallinn, Estonia 2016 / p. 123-126 : ill http://www.ester.ee/record=b2150914*est

DFT-based external test and diagnosis of mesh-like networks on chips = Testitavusel põhinev välise testi ja diagnoosi meetod kahemõõtmelistele kiipvõrkudele

Govind, Vineeth 2009 <https://digi.lib.ttu.ee/ii/?454> https://www.ester.ee/record=b2539211*est

Diagnostic modeling of digital systems with low- and high-level decision diagrams

Ubar, Raimund-Johannes LATW2013 : 14th IEEE Latin-American Test Workshop, Cordoba, Argentina, April 3-5, 2013 : [proceedings] 2013 / [1] p

Diagnostic software with WEB interface for teaching purposes

Vislogubov, Vladislav; **Jutman, Artur; Kruus, Helena; Orasson, Elmet; Raik, Jaan; Ubar, Raimund-Johannes** BEC 2004 : proceedings of the 9th Biennial Baltic Electronics Conference : October 3-6, 2004, Tallinn, Estonia 2004 / p. 255-258 : ill

Diagnostic test generation for statistical bug localization using evolutionary computation

Gaudesi, Marco; **Jenihhin, Maksim; Raik, Jaan; Tihomirov, Valentin; Ubar, Raimund-Johannes** Applications of Evolutionary Computation : 17th European Conference, EvoApplications 2014, Granada, Spain, April 23-25, 2014 : revised selected papers 2014 / p. 425-436 : ill https://doi.org/10.1007/978-3-662-45523-4_35 [Conference proceeding at Scopus](#) [Article at Scopus](#) [Conference proceeding at WOS](#) [Article at WOS](#)

DIAGNOZER : a laboratory tool for teaching research in diagnosis of electronic systems [Electronic resource]

Ubar, Raimund-Johannes; Kostin, Sergei; Jutman, Artur; Raik, Jaan; Wuttke, Heinz-Dietrich 2009 IEEE International Conference on Microelectronic Systems Education MSE '09 : 25-27 July 2009, San Francisco, California : [proceedings] 2009 / p. 12-15 : ill. [CD-ROM] <http://dx.doi.org/10.1109/MSE.2009.5270842>

Digitaalsüsteemide diagnostika

Ubar, Raimund-Johannes 2005 http://www.ester.ee/record=b2097071*est

Digital system modeling and synthesis as an introduction to computer systems engineering

Tajammul, Muhammad Adeel; Azad, Siavoosh Payandeh; Ellervee, Peeter 2015 International Conference on Microelectronic Systems Education : MSE '15 : Pittsburgh, PA, May 20-21, 2015 2015 / p. 52-55 : ill <http://dx.doi.org/10.1109/MSE.2015.7160016>

Digital test in WEB-based environment

Ivask, Eero 2006 https://www.ester.ee/record=b2158119*est

Discovering logical constructs from Estonian children language = Loogiliste konstruktsioonide avastamine eesti laste keelest

Matsak, Erika 2009 https://www.ester.ee/record=b2557755*est

Diskreetne matemaatika

Lensen, Harri; Kruus, Margus 2006 http://www.ester.ee/record=b2223858*est

Diskreetne matemaatika

Lensen, Harri; Kruus, Margus 2002 http://www.ester.ee/record=b1850141*est

Distributed approach for parallel exact critical path tracing fault simulation

Ivask, Eero; Devadze, Sergei; Ubar, Raimund-Johannes International journal of microelectronics and computer science 2010 / p. 165-174 : ill

Double phase fault collapsing with linear complexity in digital circuits

Ubar, Raimund-Johannes; Jürimägi, Lembit; Orasson, Elmet; Josifovska, Galina; Oyeniran, Adeboye Stephen DSD 2015 : 18th Euromicro Conference on Digital Systems Design : 26-28 August 2015, Funchal, Madeira, Portugal 2015 / p. 700-705 : ill

DyMeP : an infrastructure to support dynamic memory binding for runtime mapping in CGRAs

Tajammul, Muhammad Adeel; Jafri, Syed Mohammad Asad Hassan; Ellervee, Peeter; Hemani, Ahmed; Tenhunen, Hannu; Plosila, Juha 28th International Conference on VLSI Design : held concurrently with 14th International Conference on Embedded Systems : 3-7 January 2015, Bangalore, India : proceedings 2015 / p. 547-552 : ill <https://doi.org/10.1109/VLSID.2015.98> [Conference proceedings at Scopus](#) [Article at Scopus](#) [Article at WOS](#)

DyMeP : an infrastructure to support dynamic memory binding for runtime mapping in CGRAs

Tajammul, Muhammad Adeel; Jafri, Syed Mohammad Asad Hassan; Ellervee, Peeter; Hemani, Ahmed; Tenhunen, Hannu; Plosila, Juha Doctoral School in Information and Communication Technology : proceedings of doctoral session of BEC 2014 : October 6-8 2014, Laulasmaa 2014 / lk. 19-22 : ill

Dynamic quadrant partitioning adaptive routing algorithm for irregular reduced vertical link density topology 3-dimensional network-on-chips

Ying, Haoyuan; Hofmann, Klaus; Hollstein, Thomas Proceedings of the 2014 International Conference on High Performance Computing & Simulation (HPCS 2014) : July 21-25, 2014, Bologna, Italy 2014 / p. 516-522 : ill

EE : Eesti (Estonia)

Ubar, Raimund-Johannes; Rüstern, Ennu; Kruus, Margus Towards the harmonisation of Electrical and Information Engineering Education in Europe : 2003-2004 2003 / p. 67-74 : ill http://www.ester.ee/record=b2300874*est

Eestilt Euroopale : [Euroopa nanotehnika foorumil osales Eestist Raamprogrammi FP7 projekt DIAMOND, mida juhib TTÜ arvutitehnika instituudi professor Jaan Raik]

Ubar, Raimund-Johannes Mente et Manu 2012 / lk. 8 : fot https://www.ester.ee/record=b1242496*est

Effective scalable IEEE 1687 instrumentation network for fault management

Jutman, Artur; Shibin, Konstantin; Devadze, Sergei IEEE design & test 2013 / p. 26-35 : ill

<https://doi.org/10.1109/MDAT.2013.2278535> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

E-learning tools for teaching self-test of digital electronics

Jutman, Artur; Gramatova, Elena; Pikula, T.; Ubar, Raimund-Johannes 15 EAEIE International Conference on Innovation in Education for Electrical and Information Engineering : Sofia, Bulgaria, May 27-29, 2004 2004 / p. 267-272 : ill

Elektroonika kui Eesti innovatsioonisüsteemi infrastruktuur

Min, Mart; Rang, Toomas; Ubar, Raimund-Johannes Eesti teadlaste kongress, 11.-15. augustini 1996. a. Tallinnas : ettekannete kokkuvõtted 1996 / lk. 265 https://www.ester.ee/record=b1052731*est

Elmet Orasson tabab laskesporti

Orasson, Elmet Mente et Manu 2014 / lk. 18-19 : fot https://www.ester.ee/record=b1242496*est

Embedded software solutions for development of marine navigation light system = Sardtarkvara lahendused valgusnavigatsiooni süsteemide arendusel

Moorits, Erkki 2016 <http://digi.lib.ttu.ee/i/?6383>

Environment for fault simulation acceleration on FPGA

Ellervee, Peeter; Raik, Jaan; Tihomirov, Valentin BEC 2004 : proceedings of the 9th Biennial Baltic Electronics Conference : October 3-6, 2004, Tallinn, Estonia 2004 / p. 217-220 : ill

Environment for the analysis of functional self-test quality in digital systems

Ubar, Raimund-Johannes; Kostin, Sergei; Kruus, Helena; Aarna, Margit; Devadze, Sergei Proceedings of the Estonian Academy of Sciences 2014 / p. 151-162 : ill https://artiklid.elnet.ee/record=b2673964*est <https://doi.org/10.3176/proc.2014.2.05> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Estonia : e-Design and EDA

Jenihhin, Maksim 50th DAC Global Forum 2013 / [2] p

Estonian eGovernment services : lesson learned

Kalja, Ahto; Pöld, Janari; Robal, Tarmo; Vallner, Uuno; Viies, Vladimir Proceedings of PICMET'13 : Technology Management in the IT-Driven Services : [July 28-August 1, 2013, San Jose, California, USA] 2013 / p. 562-568 : ill

Evaluation of basic project management activities : study in software industry

Lepmets, Marion 2007 https://www.ester.ee/record=b2302044*est

Evaluation of SysML software for teaching systems engineering basics

Kruus, Helena; Jervan, Gert Proceedings of the 25th International Conference on European Association for Education in Electrical and Information Engineering : 30 May-June 2014, Cesme, Türkiye 2014 / p. 29-32 : ill

Evolutionary approach to the functional test generation for digital circuits

Skobtsov, Y.A.; Ivanov, D.E.; Skobtsov, V.Y.; Ubar, Raimund-Johannes BEC 2004 : proceedings of the 9th Biennial Baltic Electronics Conference : October 3-6, 2004, Tallinn, Estonia 2004 / p. 229-232 : ill

Exact static compaction of independent test sequences

Raik, Jaan; Jutman, Artur; Ubar, Raimund-Johannes BEC 2002 : proceedings of the 8th Biennial Baltic Electronics Conference : October 6-9, 2002, Tallinn, Estonia 2002 / p. 315-318 : ill

Expectations of software development practitioners for non-technical clients

Ojastu, Deniss; Robal, Tarmo; Kalja, Ahto Databases and information systems VIII : selected papers from the Eleventh International Baltic Conference, DB&IS 2014 2014 / p. 317-330 : ill <https://doi.org/10.3233/978-1-61499-458-9-317> [Conference proceedings at Scopus](#) [Article at Scopus](#) [Article at WOS](#)

Extended checkers for control part of routers in network-on-chips

Hariharan, Ranganathan; Niazmand, Behrad; Hollstein, Thomas; Raik, Jaan; Jervan, Gert MEDIAN 2015 : the 4th Workshop on Manufacturable and Dependable Multicore Architectures at Nanoscale : March 13, 2015, Grenoble, France 2015 / p. 36-39 : ill

Extended checkers for logic-based distributed routing in network-on-chips

Niazmand, Behrad; Hariharan, Ranganathan; Govind, Vineeth; Jervan, Gert; Hollstein, Thomas; Raik, Jaan Proceedings of the 8th Annual Conference of the Estonian National Doctoral School in Information and Communication Technologies : December 5-6, 2014, Rakvere 2014 / p. 83-86 : ill

Extended checkers for logic-based distributed routing in network-on-chips

Niazmand, Behrad; Hariharan, Ranganathan; Govind, Vineeth; Jervan, Gert; Hollstein, Thomas; Raik, Jaan BEC 2014 : 2014 14th Biennial Baltic Electronics Conference : proceedings of the 14th Biennial Baltic Electronics Conference : Tallinn University of Technology, October 6-8, 2014, Tallinn, Estonia 2014 / p. 77-80 : ill

Extensible open-source framework for translating RTL VHDL IP cores to SystemC

Saif Abrar, Syed; Jenihhin, Maksim; Raik, Jaan Proceedings of the 2013 IEEE 16th International Symposium on Design and Diagnostics of Electronic Circuits & Systems (DDECS) : April 8-10, 2013, Karlovy Vary, Czech Republic 2013 / p. 112-115

Fast and optimized task allocation method for low vertical link density 3-Dimensional Networks-on-Chip based many core systems

Ying, Haoyuan; **Hollstein, Thomas**; Hofmann, Klaus Proceedings : Design, Automation & Test in Europe : Grenoble, France, March 18-22, 2013 2013 / p. 1777-1782 : ill

Fast data sort based on searching networks with ring pipeline

Sklyarov, Valery; Skliarova, Iuliia; **Sudnitsõn, Aleksander** Elektronika ir elektrotehnika = Electronics and electrical engineering 2016 / p. 58-62 : ill <https://doi.org/10.5755/j01.eie.22.4.15920> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Fast extended test access via JTAG and FPGAs

Devadze, Sergei; Jutman, Artur; Aleksejev, Igor; Ubar, Raimund-Johannes International Test Conference 2009 : November 1 - November 6, 2009, Austin Convention Center, Austin, Texas USA : proceedings 2009 / p. 1-7 : ill
<http://dx.doi.org/10.1109/TEST.2009.5355668>

Fast matrix covering in all programmable systems-on-chip

Sklyarov, Valery; Skliarova, Iuliia; **Rjabov, Artjom; Sudnitsõn, Aleksander** Elektronika ir elektrotehnika = Electronics and electrical engineering 2014 / p. 150-153 : ill <https://doi.org/10.5755/j01.eee.20.5.7116> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Fast static compaction of tests composed of independent sequences : basic properties and comparison of methods

Raik, Jaan; Jutman, Artur; Ubar, Raimund-Johannes The 9th IEEE International Conference on Electronics, Circuits and Systems : ICECS 2002 : September 15-18, 2002, Dubrovnik, Croatia. Volume II 2002 / p. 445-448 : ill
<http://dx.doi.org/10.1109/ICECS.2002.1046190> <https://ieeexplore.ieee.org/document/1046190>

Fault collapsing in digital circuits using fast fault dominance and equivalence analysis with SSBDDs

Ubar, Raimund-Johannes; Jürimägi, Lembit; Orasson, Elmet; Raik, Jaan VLSI-SoC : Design for Reliability, Security, and Low Power : 23rd IFIP WG 10.5/IEEE International Conference on Very Large Scale Integration, VLSI-SoC 2015 Daejeon, Korea, October 5-7, 2015 : revised selected papers 2016 / p. 23-45 : ill https://doi.org/10.1007/978-3-319-46097-0_2 [Conference Proceedings at Scopus](#) [Article at Scopus](#) [Article at WOS](#)

Fault diagnosis in integrated circuits with BIST

Ubar, Raimund-Johannes; Kostin, Sergei; Raik, Jaan; Evertson, Teet; Lensen, Harri 10th Euromicro Conference on Digital System Design Architectures, Methods and Tools, DSD 2007 : 29-31 August 2007, Lübeck, Germany : proceedings 2007 / p. 604-610 : ill <http://dx.doi.org/10.1109/DSD.2007.4341530>

Fault effect reasoning in digital systems by topological view on low- and high-level decision diagrams

Ubar, Raimund-Johannes Вестник Томского государственного университета. Управление, вычислительная техника и информатика 2014 / p. 99-113 : ill http://journals.tsu.ru/informatics/&journal_page=archive&id=923&article_id=12107

Fault management instrumentation network based on IEEE P1687 JTAG

Shibin, Konstantin; Jutman, Artur; Devadze, Sergei European Test Symposium (ETS), 2013, Avignon, France 2013

Fault oriented test pattern generation for sequential circuits using Genetic Algorithms

Ivask, Eero; Raik, Jaan; Ubar, Raimund-Johannes The 7th Biennial Conference on Electronics and Microsystem Technology "Baltic Electronics Conference" : BEC 2000 : October 8 - 11, 2000, Tallinn, Estonia : conference proceedings 2000 / p. 129-132 : ill

Fault simulation and code coverage analysis of RTL designs using high-level decision diagrams = Rikete simuleerimine ja koodikatte analüüs register-siirde tasemel kasutades kõrgtaseme otsustusdiagramme

Reinsalu, Uljana 2013 https://www.ester.ee/record=b2963595*est

Fault simulation of digital systems = Digitaalsüsteemide rikete simuleerimine

Devadze, Sergei 2009 <https://digi.lib.ttu.ee/i/?445> https://www.ester.ee/record=b2508727*est

Fault simulation with parallel critical path tracing for combinational circuits using structurally synthesized BDDs

Devadze, Sergei; Raik, Jaan; Jutman, Artur; Ubar, Raimund-Johannes 7th IEEE Latin American Test Workshop LATW'06 : Buenos Aires, Argentina, March 26th-29th, 2006 : proceedings 2006 / p. 97-102 : ill

Fault simulation with parallel exact critical path tracing in multiple core environment

Gorev, Maksim; Ubar, Raimund-Johannes; Devadze, Sergei 2015 Design, Automation & Test in Europe Conference & Exhibition (DATE) : proceedings 2015 / p. 1180-1185 : ill

Fault-tolerant scheduling of mixed-critical applications on multi-processor platforms

Bagheri, Mehrdad; **Jervan, Gert** 2014 International Conference on Embedded and Ubiquitous Computing : EUC 2014 : 26-28 August 2014, Milano, Italy : proceedings 2014 / p. 25-32 : ill

Finite state machine synthesis for low power using input-disabling precomputation architectures

Sudnitsõn, Aleksander The 7th Biennial Conference on Electronics and Microsystem Technology "Baltic Electronics Conference" : BEC 2000 : October 8 - 11, 2000, Tallinn, Estonia : conference proceedings 2000 / p. 137-140 : ill

Flexible controller for educational robot kit

Ruberg, Priit; Guitar, Aivar; Ellervee, Peeter 2015 International Conference on Microelectronic Systems Education : MSE '15 : Pittsburgh, PA, May 20-21, 2015 2015 / p. 17-20 : ill <http://dx.doi.org/10.1109/MSE.2015.7160007>

Foreword

Rang, Toomas; Min, Mart; Ubar, Raimund-Johannes BEC'96 : the 5th Biennial Baltic Electronics Conference, October 7-11, 1996, Tallinn, Estonia : proceedings 1996 / p. 3 https://www.ester.ee/record=b2150914*est

Foreword to the 12th IEEE DDECS Symposium

Pliva, Zdenek; Manhaeve, Hans; Renovell, Michel; Novak, Ondrej; **Ubar, Raimund-Johannes**; Drabkova, Jindra Proceedings of the 2009 IEEE Symposium on Design and Diagnostics of Electronic Circuits and Systems : April 15-17, 2009, Liberec, Czech Republic 2009 / p. iii <http://dx.doi.org/10.1109/DDECS.2009.5012081>

Formal verification and error correction on high-level decision diagrams = Formaalne verifitseerimine ja vigade parandamine kõrgtasemelistel otsustusdiagrammidel

Karputkin, Anton 2012

FP7 DIAMOND : design error diagnosis and correction success stories

Raik, Jaan; Jenihhin, Maksim; Könighofer, Robert European Test Symposium (ETS), 2013, Avignon, France 2013 / p. 1-6

FPGA-based accelerators for parallel data sort

Sklyarov, Valery; Skliarova, Ioulia; **Sudnitsõn, Aleksander** Applied computer systems 2014 / p. 53-63 : ill

FPGA-based embedded virtual instrumentation = FPGA-sisesed virtuaalsed test- ja mõõtevahendid

Aleksejev, Igor 2013 http://www.ester.ee/record=b2927687*est

FPGA-based time and cost effective Hamming weight comparators for binary vectors

Sklyarov, Valery; Skliarova, Ioulia; **Sudnitsõn, Aleksander; Kruus, Margus** Proceedings : EUROCON 2015 : Salamanca, Spain, 8th-11th September 2015 / p. 328-333 : ill <http://dx.doi.org/10.1109/EUROCON.2015.7313700>

A framework for area-efficient concurrent online checkers design

Saltarelli, Pietro; Niazmand, Behrad; Hariharan, Ranganathan; Raik, Jaan; Jervan, Gert; Hollstein, Thomas MEDIAN Finale : Workshop on Manufacturable and Dependable Multicore Architectures at Nanoscale : November 10-11, 2015, Tallinn, Estonia 2015 / p. 64-69 : ill

A framework for combining concurrent checking and online embedded test for low-latency fault detection in NoC routers

Saltarelli, Pietro; Niazmand, Behrad; Raik, Jaan; Govind, Vineeth; Hollstein, Thomas; Jervan, Gert; Hariharan, Ranganathan NOCS '15 : International Symposium on Networks-on-Chip : Vancouver, BC, Canada, September 28-30, 2015 2015 / [8] p. : ill <http://dx.doi.org/10.1145/2786572.2788713>

A framework for comprehensive automated evaluation of concurrent online checkers

Saltarelli, Pietro; Niazmand, Behrad; Raik, Jaan; Hariharan, Ranganathan; Jervan, Gert; Hollstein, Thomas Euromicro Conference on Digital System Design : DSD 2015 : 26-28 August 2015, Funchal, Madeira, Portugal : proceedings 2015 / p. 288-292 : ill <http://dx.doi.org/10.1109/DSD.2015.15>

A framework for improving web application user interfaces through immediate evaluation

Marenkov, Jevgeni; Robal, Tarmo; Kalja, Ahto Databases and information systems IX : selected papers from the twelfth International Baltic Conference, DB&IS 2016 2016 / p. 283-296 : ill <https://doi.org/10.3233/978-1-61499-714-6-283> [Article collection metrics at Scopus](#) [Article at Scopus](#) [Article at WOS](#)

A framework of awareness for artificial subjects

Jantsch, Axel; Tammemäe, Kalle CODES '14 : proceedings of the 2014 International Conference on Hardware/Software Codesign and System Synthesis 2014 / [3] p

FSM decomposition using shift registers

Kruus, Margus; Lensen, Harri The 7th Biennial Conference on Electronics and Microsystem Technology "Baltic Electronics Conference" : BEC 2000 : October 8 - 11, 2000, Tallinn, Estonia : conference proceedings 2000 / p. 141-144 : ill

FSMD RTL design manipulation for clock interface abstraction

Abrar, Syed Saif; Jenihhin, Maksim; Raik, Jaan 2015 International Conference on Advances in Computing, Communications and Informatics (ICACCI) : 10-13 August 2015, Kerala, India 2015 / p. 463-468 : ill <http://dx.doi.org/10.1109/ICACCI.2015.7275652>

Functional self-test of high-performance pipe-lined signal processing architectures

Gorev, Maksim; Ubar, Raimund-Johannes; Ellervee, Peeter; Devadze, Sergei; Raik, Jaan; Min, Mart Microprocessors and microsystems 2015 / p. 909-918 : ill <https://doi.org/10.1016/j.micpro.2014.11.002> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Functional test generation for finite state machines

Ubar, Raimund-Johannes; Brik, Marina; Jutman, Artur; Raik, Jaan; Bengtsson, Tomas; Kumar, Shashi BEC 2006 : 2006 International Baltic Electronics Conference : Tallinn University of Technology, October 2-4, 2006, Tallinn, Estonia : proceedings of the 10th Biennial Baltic Electronics Conference 2006 / p. 205-208 : ill

GA-based test generation for sequential circuits

Brik, Marina; Raik, Jaan; Ubar, Raimund-Johannes; Ivask, Eero Proceedings of East-West Design & Test Workshop (EWDWTW'04) : Yalta, Alushta, Crimea, Ukraine, September 23-26, 2004 2004 / p. 30-34

Gate-level modelling of NBTI-induced delays under process variations

Copetti, Thiago; Cardoso Medeiros, Guilherme; Bolzani Poehls, Leticia; Vargas, Fabian; Kostin, Sergei; Jenihhin, Maksim; Raik, Jaan; Ubar, Raimund-Johannes LATS 2016 : 17th IEEE Latin-American Test Symposium, Foz do Iguaçu, Brazil, 6th-9th April 2016 2016 / p. 75-80 : ill <http://dx.doi.org/10.1109/LATW.2016.7483343>

A generic synthesizable NoC switch with a scalable testbench

Govind, Vineeth; Raik, Jaan; Ubar, Raimund-Johannes BEC 2006 : 2006 International Baltic Electronics Conference : Tallinn University of Technology, October 2-4, 2006, Tallinn, Estonia : proceedings of the 10th Biennial Baltic Electronics Conference 2006 / p. 91-94 : ill

Graph embedding in boolean hypercube

Fomina, Jelena; Zakrevskij, Arkadij BEC 2006 : 2006 International Baltic Electronics Conference : Tallinn University of Technology, October 2-4, 2006, Tallinn, Estonia : proceedings of the 10th Biennial Baltic Electronics Conference 2006 / p. 131-134 : ill

Greedy alternative for the static compaction of sequential circuit test sequences

Raik, Jaan The 7th Biennial Conference on Electronics and Microsystem Technology "Baltic Electronics Conference" : BEC 2000 : October 8 - 11, 2000, Tallinn, Estonia : conference proceedings 2000 / p. 133-136 : ill

Grey box identification of fractional-order system models from frequency domain data

Tepljakov, Aleksei; Petlenkov, Eduard; Belikov, Juri 41th International Conference on Telecommunications and Signal Processing : July 4-6, 2018, Athens, Greece : proceedings 2018 / p. 319-322 : ill <https://doi.org/10.1109/TSP.2018.8441247>

GSNoC — the comprehensive design platform for 3-dimensional Networks-on-Chip based many core embedded systems

Ying, Haoyuan; Hollstein, Thomas; Hofmann, Klaus Proceedings of the 2013 International Conference on High Performance Computing & Simulation (HPCS 2013) : July 1-July 5, 2013, Helsinki, Finland 2013 / p. 217-223 : ill

Guest editorial

Ellervee, Peeter; Nurmi, Jari Microprocessors and microsystems 2013 / p. 430-431

Hardware accelerators for information retrieval and data mining

Sklyarov, Valery; Skliarova, Ioulia; Silva, João; Sudnitsõn, Aleksander; Rjabov, Artjom 2015 International Conference on Information and Communication Technology Research (ICTRC2015) : Abu Dhabi, United Arab Emirates, May 17-19, 2015 2015 / p. 202-205 : ill <http://dx.doi.org/10.1109/ICTRC.2015.7156457>

Hardware close programming for freshmen

Kruus, Helena; Brik, Marina; Kruus, Margus; Ruberg, Priit; Viies, Vladimir; Ellervee, Peeter 10th European Workshop on Microelectronics Education : EWME 2014 : May 14-16, 2014, Tallinn, Estonia 2014 / p. 93-96 : ill

Hardware implementation of face recognition using low precision representation

Dwivedi, Sai Kumar; **Azad, Siavoosh Payandeh; Ellervee, Peeter**; Dash, Ratnakar BEC 2016 : 2016 15th Biennial Baltic Electronics Conference : proceedings of the 15th Biennial Baltic Electronics Conference : Tallinn University of Technology, October 3-5, 2016, Tallinn, Estonia 2016 / p. 63-66 : ill http://www.ester.ee/record=b2150914*est

Hardware implementation of recursive sorting algorithms using tree-like structures and HFSM models = Rekursiivsete sortimisalgoritmide riistvaraline realiseerimine kasutades puulaadseid struktuure ja HFSM mudeleid

Mihhailov, Dmitri 2011 https://www.ester.ee/record=b2748823*est

Hardware modeling for design verification and debug = Riistvara modelleerimine disaini verifitseerimise ja silumise jaoks

Tšepurov, Anton 2013 https://www.ester.ee/record=b2963501*est

Hardware/software co-design for programmable systems-on-chip

Sklyarov, Valery; Skliarova, Iuliia; Silva, João; Rjabov, Artjom; **Sudnitsõn, Aleksander**; Cardoso, Cláudia 2014 http://www.ester.ee/record=b3087107*est

Hardware/software co-design in extensible processing platforms for combinatorial search algorithms

Skliarova, Iuliia; Sklyarov, Valery; **Rjabov, Artjom; Sudnitsõn, Aleksander** MELECON 2014 : 2014 17th IEEE Mediterranean Electrotechnical Conference : 13-16 April 2014, Beirut, Lebanon 2014 / p. 462-466 : ill <https://doi.org/10.1109/MELCON.2014.6820578>
[Conference proceedings at Scopus](#) [Article at Scopus](#) [Article at WOS](#)

A hardware/software co-design reconfigurable network-on-chip FPGA emulation method

Ying, Haoyuan; **Hollstein, Thomas**; Hofmann, Klaus 2014 9th International Symposium on Reconfigurable and Communication-Centric Systems-on-Chip (ReCoSoC) : Montpellier, France, 26-28 May, 2014 2014 / [8] p. : ill

Hardware-based systems for partial sorting of streaming data

Rjabov, Artjom BEC 2016 : 2016 15th Biennial Baltic Electronics Conference : proceedings of the 15th Biennial Baltic Electronics Conference : Tallinn University of Technology, October 3-5, 2016, Tallinn, Estonia 2016 / p. 59-62 : ill
http://www.ester.ee/record=b2150914*est

Hierarchical fault diagnosis in embedded digital systems with multi-level decision diagrams [Electronic resource]

Ubar, Raimund-Johannes; Ewartson, Teet; Lensen, Harri; Aarna, Margit 5th International Conference on Industrial Automation = Cinquieme Conference Internationale sur l'Automatisation Industrielle : June 11-13, 2007, Montreal, Canada 2007 / [6] p. [CD-ROM]

Hierarchical fault simulation for finite state machines

Brik, Marina; Raik, Jaan; Ubar, Raimund-Johannes The 7th Biennial Conference on Electronics and Microsystem Technology "Baltic Electronics Conference" : BEC 2000 : October 8 - 11, 2000, Tallinn, Estonia : conference proceedings 2000 / p. 145-148 : ill

Hierarchical identification of NBTI-critical gates in nanoscale logic

Kostin, Sergei; Raik, Jaan; Ubar, Raimund-Johannes; Jenihhin, Maksim LATW2014 : 15th IEEE Latin-American Test Workshop : Fortaleza, Brazil, March 12th-15th, 2014 2014 / [6] p. : ill

Hierarchical identification of untestable faults in sequential circuits

Raik, Jaan; Ubar, Raimund-Johannes; Krivenko, Anna; Kruus, Margus 10th Euromicro Conference on Digital System Design Architectures, Methods and Tools, DSD 2007 : 29-31 August 2007, Lübeck, Germany : proceedings 2007 / p. 668-671 : ill
<http://dx.doi.org/10.1109/DSD.2007.4341539>

Hierarchical test generation for digital circuits represented by Decision Diagrams : thesis on informatics and system engineering

Raik, Jaan 2001 https://www.ester.ee/record=b1578107*est

Hierarchical test pattern generation and untestability identification techniques for synchronous sequential circuits = Hierarhilised testintegreerimise ja mittetestitavuse identifitseerimise meetodid sünkroonsetele järjestikskeemidele

Rannaste, Anna 2010 https://www.ester.ee/record=b2637391*est

High-level decision diagram based fault models for targeting FSMs

Raik, Jaan; Ubar, Raimund-Johannes; Viilukas, Taavi 9th EUROMICRO Conference on Digital Systems Design : Architectures, Methods and Tools (DSD 2006) : 30 August 2006-1 September 2006, Cavtat near Dubrovnik, Croatia : proceedings 2006 / p. 353-358 : ill <http://dx.doi.org/10.1109/DSD.2006.60>

High-level decision diagrams based coverage metrics for verification and test

Jenihhin, Maksim; Raik, Jaan; Tšepurov, Anton; Reinsalu, Uljana; Ubar, Raimund-Johannes LATW 2009 : 10th IEEE Latin

American Test Workshop : Buzios, Rio de Janeiro, Brazil, March 2-5, 2009 / [6] p. : ill <http://dx.doi.org/10.1109/LATW.2009.4813792>

High-level design error diagnosis using backtrace on decision diagrams

Raik, Jaan; Repinski, Urmaz; Ubar, Raimund-Johannes; Jenihhin, Maksim; Tšepurov, Anton 28th NORCHIP Conference : Tampere, Finland, 15-16 November 2010 : conference program and papers 2010 / [4] p. : ill <http://dx.doi.org/10.1109/NORCHIP.2010.5669486>

High-level modeling and testing of multiple control faults in digital systems

Jasnetski, Artjom; Oyeniran, Adeboye Stephen; Tšertov, Anton; Schölzel, Mario; Ubar, Raimund-Johannes Formal proceedings of the 2016 IEEE 19th International Symposium on Design and Diagnostics of Electronic Circuits & Systems (DDECS) : April 20-22, 2016, Košice, Slovakia 2016 / [6] p. : ill <http://dx.doi.org/10.1109/DDECS.2016.7482445>

High-level synthesis and test in the MOSCITO-based virtual laboratory

Schneider, Andre; Diener, Karl-Heinz; **Jervan, Gert**; Peng, Z.; **Raik, Jaan; Ubar, Raimund-Johannes**; Hollstein, Thomas; Glesner, M. BEC 2002 : proceedings of the 8th Biennial Baltic Electronics Conference : October 6-9, 2002, Tallinn, Estonia 2002 / p. 287-290 : ill

High-level synthesis of control and memory intensive applications : thesis submitted to the Royal Institute of Technology in partial fulfillment of the requirements for the degree of Doctor of Technology
Ellervee, Peeter 2000

High-performance information processing in distributed computing systems

Sklyarov, Valery; **Rjabov, Artjom**; Skliarova, Iuliia; **Sudnitsõn, Aleksander** International journal of innovative computing, information and control 2016 / p. 139-160 : ill https://www.researchgate.net/publication/297047447_High-performance_information_processing_in_distributed_computing_systems [Journal metrics at Scopus](#) [Article at Scopus](#)

Holistic approach for Fault-Tolerant Network-on-Chip based many-core systems [Online resource]

Azad, Siavoosh Payandeh; Niazmand, Behrad; Raik, Jaan; Jervan, Gert; Hollstein, Thomas arXiv.org 2016 / [8] p. : ill

How to generate high quality tests for digital systems

Ubar, Raimund-Johannes; Aarna, Margit; Kruus, Helena; Raik, Jaan 2004 International Semiconductor Conference : 27th edition, October 4-6, 2004, Sinaia, Romania : CAS 2004 proceedings. Volume 2 2004 / p. 459-462 : ill <http://dx.doi.org/10.1109/SMICND.2004.1403048>

Hybrid BIST optimization using reseeding and test set compaction

Jervan, Gert; Orasson, Elmet; Kruus, Helena; Ubar, Raimund-Johannes 10th Euromicro Conference on Digital System Design Architectures, Methods and Tools, DSD 2007 : 29-31 August 2007, Lübeck, Germany : proceedings 2007 / p. 596-603 : ill <http://dx.doi.org/10.1109/DSD.2007.4341529>

Hybrid BIST scheduling for NoC-based SoCs

Jervan, Gert; Shchenova, Tatjana; Ubar, Raimund-Johannes Proceedings [of] 24th IEEE NORCHIP Conference : Linköping, Sweden, 20-21 November 2006 2006 / p. 141-144 : ill <https://ieeexplore.ieee.org/document/4126966>

Hybrid built-in self-test : methods and tools for analysis and optimization of BIST = Sisseehitatud hübriidne isetestimine : meetodid ja vahendid analüüsiks ning optimeerimiseks

Orasson, Elmet 2007 https://www.eester.ee/record=b2305436*est

Hybrid functional BIST for digital systems

Mazurova, Natalja; Smahtina, Julia; Ubar, Raimund-Johannes BEC 2004 : proceedings of the 9th Biennial Baltic Electronics Conference : October 3-6, 2004, Tallinn, Estonia 2004 / p. 205-208 : ill

Identification and rejuvenation of NBTI-critical logic paths in nanoscale circuits

Jenihhin, Maksim; Squillero, Giovanni; **Tihomirov, Valentin; Kostin, Sergei; Raik, Jaan; Ubar, Raimund-Johannes** Journal of electronic testing : theory and applications (JETTA) 2016 / p. 273-289 : ill <https://doi.org/10.1007/s10836-016-5589-x> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Identification and rejuvenation of NBTI-critical paths in nanoscale logic circuits

Jenihhin, Maksim 1st International Workshop on Reliability and Aging in Forthcoming Electronic Systems : May 28-29, 2015, Cluj-Napoca, Romania 2015 / [1] p

Identifying NBTI-critical paths in nanoscale logic

Ubar, Raimund-Johannes; Vargas, Fabian; **Jenihhin, Maksim; Raik, Jaan; Kostin, Sergei**; Bolzani Poehls, Leticia 16th Euromicro Conference series on Digital System Design : DSD 2013 : proceedings : 4-6 September 2013, Santander, Spain 2013 / p. 136-141 : ill

IEEE Eesti seksioon on 10-aastane

Tammemäe, Kalle; Kukk, Vello Elektriala 2016 / lk. 14-15 http://www.estee.ee/record=b1240496*est
https://artiklid.elnet.ee/record=b2803323*est

IEEE Student Branch Tallinn University of Technology

Tammemäe, Kalle Studioosus 2014 / lk. 12 https://www.estee.ee/record=b1558644*est

Implementation of parallel operations over streams in extensible processing platforms

Sklyarov, Valery; Skliarova, Iuliia; **Rjabov, Artjom; Sudnitsõn, Aleksander** 2013 IEEE 56th International Midwest Symposium on Circuits and Systems (MWSCAS) : August 4-7, 2013, Columbus, Ohio : [proceedings] 2013 / p. 852-855 : ill
<https://doi.org/10.1109/MWSCAS.2013.6674783> [Conference Proceedings at Scopus](#) [Article at Scopus](#)

Implementing quality assessment model in IT project

Marenkov, Mihhail; Valdlo, Taavi; **Viies, Vladimir** EURAS proceedings 2014 : cooperation between standardisation organisations and the scientific and academic community 2014 / p. 107-120

Improved VHDL input for high-level synthesis tool xTractor

Ellervee, Peeter; Ivask, Eero; Kruus, Margus BEC 2006 : 2006 International Baltic Electronics Conference : Tallinn University of Technology, October 2-4, 2006, Tallinn, Estonia : proceedings of the 10th Biennial Baltic Electronics Conference 2006 / p. 87-90 : ill

Improving sophisticated self-service portal user interfaces : a study on user click behaviour

Marenkov, Jevgeni; **Robal, Tarmo; Kalja, Ahto** Databases and Information Systems : proceedings of the 11th International Baltic Conference, Baltic DB&IS 2014 : Tallinn, Estonia, 8-11 June, 2014 2014 / p. 159-170 : ill

Increasing the speed of delay simulation in digital circuits

Ubar, Raimund-Johannes; Jutman, Artur The 7th Biennial Conference on Electronics and Microsystem Technology "Baltic Electronics Conference" : BEC 2000 : October 8 - 11, 2000, Tallinn, Estonia : conference proceedings 2000 / p. 31-34 : ill

Informaatika teoreetilised alused : struktuurne aspekt

Lorents, Peeter 2001 https://www.estee.ee/record=b1056267*est

Infotehnika teaduskond : lühiteave

1998 http://www.estee.ee/record=b1061288*est

In-system programming of non-volatile memories on microprocessor-centric boards

Tšertov, Anton; Devadze, Sergei; Jutman, Artur; Jasnetski, Artjom International journal of microelectronics and computer science 2014 / p. 25-34 : ill

Integrated design and test generation under Internet based environment MOSCITO

Schneider, Andre; **Ivask, Eero; Ubar, Raimund-Johannes** Euromicro Symposium on Digital System Design : Architectures, Methods and Tools : September 4-6, 2002, Dortmund, Germany : proceedings 2002 / p. 187-194 : ill
<http://dx.doi.org/10.1109/DSD.2002.1115368>

Integrated modelling, fault management, verification and reliable design environment for cyber-physical systems

Raik, Jaan; Rauwerda, Gerard; Zhao, Yong; Shibin, Konstantin MEDIAN Finale : Workshop on Manufacturable and Dependable Multicore Architectures at Nanoscale : November 10-11, 2015, Tallinn, Estonia 2015 / p. 74

Integration of high-level synthesis to the courses on reconfigurable digital systems

Sklyarov, Valery; Skliarova, Iuliia; **Sudnitsõn, Aleksander; Kruus, Margus** 2015 38th International Convention on Information and Communication Technology, Electronics and Microelectronics (MIPRO) : May 25-29, 2015, Opatija, Croatia : proceedings 2015 / p. 166-171 : ill <http://dx.doi.org/10.1109/MIPRO.2015.7160258>

Interactions of Zynq-7000 devices with general purpose computers through PCI-express : a case study [Electronic resource]

Rjabov, Artjom; Sudnitsõn, Aleksander; Sklyarov, Valery; Skliarova, Iuliia Proceedings of the 18th Mediterranean Electrotechnical Conference MELECON 2016 : 18-20 April 2016, Limassol, Cyprus 2016 / [4] p. : ill. [CD-ROM]
<https://doi.org/10.1109/MELCON.2016.7495400>

Internet-based testability-driven test generation in the virtual environment MOSCITO

Schneider, Andre; Diener, Karl-Heinz; Elst, G.; **Ivask, Eero; Raik, Jaan; Ubar, Raimund-Johannes** International Federation for Information Processing IFIP : International Workshop on IP-Based SoC Design 2002 : proceedings : Grenoble, October 30-31, 2002 2002 / p. 357-362 : ill <http://publica.fraunhofer.de/dokumente/N-287433.html>

Investigation and development of test generation methods for control part of digital systems

Brik, Marina 2002 http://www.estee.ee/record=b1688656*est

Involving students in teaching process — encouraging student-generated content in ICT studies

Kruus, Helena; Ellervee, Peeter; Robal, Tarmo; Ruberg, Priit; Kruus, Margus Proceedings of the 24th International Conference on European Association for Education in Electrical and Information Engineering : 30-31 May 2013, Chania, Greece 2013 / p. 76-81 : ill

Jaak Aaviksoo tuleb rektoriks kinnitada

Jervan, Gert Eesti Päevaleht 2015 / lk. 11 <https://epl.delfi.ee/artikkel/71821559/jaak-aaviksoo-tuleb-rektoriks-kinnitada>

Java technology based training system for teaching digital design and test

Devadze, Sergei; Jutman, Artur; Sudnitsõn, Aleksander; Ubar, Raimund-Johannes; Wuttke, Heinz-Dietrich BEC 2002 : proceedings of the 8th Biennial Baltic Electronics Conference : October 6-9, 2002, Tallinn, Estonia 2002 / p. 283-286 : ill

Kahekiiruselise mitmemöötmelise diskreetse objekti uurimine : [magistritöö] : õppesuund: arvuti- ja süsteemitehnika

Astrov, Igor 1992 http://www.ester.ee/record=b2676838*est

Kakskümmend aastat hiljem : [vestlus arvutisüsteemide dignostika ja verifitseerimise õppetooli professori Jaan Raikiga]

Raik, Jaan Mente et Manu 2013 / lk. 10-12 : fot https://www.ester.ee/record=b1242496*est

20 aastat maailma testiteaduse tippkonkurents

Ubar, Raimund-Johannes Mente et Manu 2015 / lk. 12-13 : fot https://artiklid.elnet.ee/record=b2749536*est

Kas oleme õigel teel?

Ubar, Raimund-Johannes Sirp 2016 / lk. 10-11 <https://www.sirp.ee/s1-artiklid/c21-teadus/kas-oleme-oigel-teel/>

Keel ja loogika

Lorents, Peeter 2000 https://www.ester.ee/record=b1372695*est

Kuidas fookustada korraga kaugele ja lähedale, ehk, Kuidas ülikool saaks paremini teenida ühiskonda

Ubar, Raimund-Johannes Tallinna Tehnikaülikooli aastaraamat 2009 2010 / lk. 13-15 https://www.ester.ee/record=b1212786*est

Kuidas teemant tehnikaülikooli tuli

Raik, Jaan Tallinna Tehnikaülikooli aastaraamat 2009 2010 / lk. 40-43 : ill https://www.ester.ee/record=b1212786*est

Laboratory framework TEAM for investigating the dependability issues of microprocessor systems

Jasnetski, Artjom; Tšertov, Anton; Ubar, Raimund-Johannes; Kruus, Helena 10th European Workshop on Microelectronics Education : EWME 2014 : May 14-16, 2014, Tallinn, Estonia 2014 / p. 80-83 : ill

Layout to logic defect analysis for hierarchical test generation

Jenihhin, Maksim; Raik, Jaan; Ubar, Raimund-Johannes; Pleskacz, Witold A.; Rakowski, Michal Proceedings of the 2007 IEEE Workshop on Design and Diagnostic Circuits and Systems : April 11-13, 2007, Krakow, Poland 2007 / p. 35-40 : ill
<http://dx.doi.org/10.1109/DDECS.2007.4295251>

LFSR polynomial and seed selection using genetic algorithm

Aleksejev, E.; Jutman, Artur; Ubar, Raimund-Johannes BEC 2006 : 2006 International Baltic Electronics Conference : Tallinn University of Technology, October 2-4, 2006, Tallinn, Estonia : proceedings of the 10th Biennial Baltic Electronics Conference 2006 / p. 179-182 : ill

Logic simulation and fault collapsing with shared structurally synthesized BDDs

Mironov, Dmitri; Ubar, Raimund-Johannes; Raik, Jaan 2014 19th IEEE European Test Symposium (ETS) : May 26th-30th, 2014, Paderborn, Germany : proceedings 2014 / [2] p. : ill

Logic-based implementation of fault-tolerant routing in 3D Network-on-Chips

Niazmand, Behrad; Azad, Siavoosh Payandeh; Flich, Jose; Raik, Jaan; Jervan, Gert; Hollstein, Thomas 2016 Tenth IEEE/ACM International Symposium on Networks-on-Chip (NOCS) : Nara, Japan, 31 August - 2 September 2016 2016 / [8] p. : ill
<https://doi.org/10.1109/NOCS.2016.7579317>

Loodetavasti ajame ühist asja

Kruus, Margus Mente et Manu 2016 / lk. 4-5 : fot https://artiklid.elnet.ee/record=b2756897*est

Low power finite state machine synthesis

Fomina, Jelena 2005 https://www.ester.ee/record=b2097121*est

Lower bounds of the size of shared structurally synthesized BDDs

Ubar, Raimund-Johannes; Mironov, Dmitri Proceedings of the 2014 IEEE 17th International Symposium on Design and Diagnostics of Electronic Circuits & Systems (DDECS) : April 23-25, 2014, Warsaw, Poland 2014 / p. 77-82 : ill

Läti keelel on teadustöös suurem roll kui eesti keelel

Haav, Hele-Mai; Kalja, Ahto; Nöges, Krõõt Mente et Manu 2014 / lk. 16-17 : fot https://artiklid.elnet.ee/record=b2674038*est

Macro level defect-oriented diagnosability of digital circuits

Kostin, Sergei; Ubar, Raimund-Johannes; Raik, Jaan BEC 2010 : 2010 12th Biennial Baltic Electronics Conference : proceedings of the 12th Biennial Baltic Electronics Conference : Tallinn University of Technology, October 4-6, 2010, Tallinn, Estonia 2010 / p. 149-152 : ill

Managing knowledge in Web portals for improved customer loyalty and satisfaction

Robal, Tarmo; Kalja, Ahto Proceedings of PICMET'13 : Technology Management in the IT-Driven Services : [July 28-August 1, 2013, San Jose, California, USA] 2013 / p. 1207-1216 : ill

Managing software engineering competences with domain ontology for customer and team profiling and training

Robal, Tarmo; Ojastu, Deniss; Kalja, Ahto; Jaakkola, Hannu PICMET '15 : proceedings : Management of the Technology Age 2015 / p. 1369-1376 : ill <http://dx.doi.org/10.1109/PICMET.2015.7273171>

Managing software engineering competences with domain ontology for customer and team profiling and training

Robal, Tarmo; Ojastu, Deniss; Kalja, Ahto; Jaakkola, Hannu PICMET '15 Conference : Management of the Technology Age : August 2-6, 2015, Portland, Oregon, USA : conference bulletin 2015 / p. 62

Mapping of VHDL structures for generic EDA database format IRSYD

Ivask, Eero; Ellervee, Peeter The 7th Biennial Conference on Electronics and Microsystem Technology "Baltic Electronics Conference" : BEC 2000 : October 8 - 11, 2000, Tallinn, Estonia : conference proceedings 2000 / p. 317-320 : ill

Measuring and identifying aging-critical paths in FPGAs

Pfeifer, Petr; Raik, Jaan; Jenihhin, Maksim; Ubar, Raimund-Johannes; Pliva, Zdenek MEDIAN 2015 : the 4th Workshop on Manufacturable and Dependable Multicore Architectures at Nanoscale : March 13, 2015, Grenoble, France 2015 / p. 56-61 : ill

A method for crosstalk fault detection in on-chip buses

Bengtsson, Tomas; Jutman, Artur; Ubar, Raimund-Johannes; Kumar, Shashi Norchip : proceedings : Oulu, Finland, 21-22 November 2005 2005 / p. 285-288 : ill <https://doi.org/10.1109/NORCHIP.2005.1597045>

Methode et outil de prototypage des systemes integres sur FPGAs : [doktoriväitekirj]

Krupnova, Helena 1999

Microcontroller energy consumption estimation based on software analysis for embedded systems

Ruberg, Priit; Lass, Keijo; Ellervee, Peeter 2015 Nordic Circuits and Systems Conference (NORCAS) : NORCHIP & International Symposium on System-on-Chip (SoC) : 1st IEEE NORCAS Conference : 26-28 October 2015, Oslo, Norway 2015 / [4] p. : ill <http://dx.doi.org/10.1109/NORCHIP.2015.7364397>

Microprocessor-based system test using debug interface

Devadze, Sergei; Jutman, Artur; Tšertov, Anton; Instenberg, Martin; Ubar, Raimund-Johannes 26th Norchip Conference : Tallinn, Estonia, 17-18 November 2008 : formal proceedings 2008 / p. 98-101 : ill <http://dx.doi.org/10.1109/NORCHIP.2008.4738291>

Mida peaks teaduspoliitikas reformima? : kui hindamisel jääb puudu kompetentsusest, on bibliomeetria see faktor, mis alati kõneleb täiel häälel ja vastuvaidlematult

Ubar, Raimund-Johannes Sirp 2014 / lk. 34-35 <https://www.sirp.ee/s1-artiklid/c9-sotsiaalia/mida-peak-teaduspoliitikas-reformima/>

Mida vinget tõi lõppev aasta tehnikailma? : [2016. aasta olulisematest uuendustest tehnoloogiamaaailmas : ekspertidena vastavad Gert Jervan, Argo Virkebau, ... Maarja Kruusmaa jt.]

Pau, Aivar Postimees 2016 / lk. 24-25 : ill

Mikrokontrollerite M68HC11 ja Satt Con 05 riist- ja tarkvara : metoodiline materjal

Tammemäe, Kalle; Toomsalu, Arvo 1995 https://www.ester.ee/record=b1069449*est

Mikroprotsessorsüsteemid : kursuseprojekti juhendmaterjal

Toomsalu, Arvo 1998 https://www.ester.ee/record=b1061287*est

Mikroprotsessorsüsteemid : kursuseprojekti metoodiline juhend

Toomsalu, Arvo 1996 https://www.ester.ee/record=b1619347*est

Miniaturized wireless monitor for long-term monitoring of newborns

Leier, Mairo; Jervan, Gert BEC 2014 : 2014 14th Biennial Baltic Electronics Conference : proceedings of the 14th Biennial Baltic Electronics Conference : Tallinn University of Technology, October 6-8, 2014, Tallinn, Estonia 2014 / p. 193-196 : ill

Mining and modelling web user engagement : a survey on academic sites for framework establishment [Electronic resource]

Robal, Tarmo; Kalja, Ahto PICMET '16 : Portland International Conference on Management of Engineering and Technology : proceedings. Technology Management for Social Innovation 2016 / p. 1942-1952 : ill. [USB]
<https://doi.org/10.1109/PICMET.2016.7806759>

A model for users' action prediction based on locality profiles

Robal, Tarmo; Kalja, Ahto Information systems development : challenges in practice, theory and education. Volume 1 2009 / p. 169-182 https://link.springer.com/chapter/10.1007/978-0-387-68772-8_14

Modeling sequential circuits with shared structurally synthesized BDDs

Ubar, Raimund-Johannes; Marenkov, Mihail; Mironov, Dmitri; Viies, Vladimir Proceedings of 2014 9th International Design & Test Symposium (IDT) : Sheraton Club des Pins Hotel, Algiers, Algeria, December 16-18, 2014 2014 / p. 130-135 : ill

Modelling of multirate multivariable control systems : a state-space approach : thesis submitted to Tallinn Technical University in candidature for the degree of Doctor of Philosophy in Engineering

Astrov, Igor 2000 http://www.ester.ee/record=b1707861*est

A modular 6LoWPAN-based wireless sensor body area network for health-monitoring applications

Le Moullec, Yannick; Lecat, Yoann; Annus, Paul; Land, Raul; Kuusik, Alar; Reidla, Marko; Hollstein, Thomas; Reinsalu, Uljana; Tammemäe, Kalle; Ruberg, Priit APSIPA ASC 2014 : Asia-Pacific Signal and Information Processing Association Annual Summit and Conference 2014 : December 9-12, 2014, Siem Reap, city of Angkor Wat, Cambodia 2014 / [4] p. : ill

Morphable compression architecture for efficient configuration in CGRAs

Jafri, Syed Mohammad Asad Hassan; Tajammul, Muhammad Adeel; Ellervee, Peeter 2014 17th Euromicro Conference on Digital System Design : DSD 2014 : 27-29 August 2014, Verona, Italy : proceedings 2014 / p. 42-49 : ill

Motivation-driven learning processes at the example of embedded systems

Hollstein, Thomas; Reinsalu, Uljana; Leier, Mairo 10th European Workshop on Microelectronics Education : EWME 2014 : May 14-16, 2014, Tallinn, Estonia 2014 / p. 3-6 : ill

A multilevel modelling environment for machine elements design

Kalja, Ahto; Kindel, Kristiina; Tiidemann, Mart; Tiidemann, Tiit OST-01 Symposium on Machine Design : Tallinn, Estonia, October 4-5, 2001 : proceedings 2001 / p. 45-50 : ill https://www.ester.ee/record=b1642353*est

Multiple control fault testing in digital systems with high-level decision diagrams

Ubar, Raimund-Johannes; Oyeniran, Adeboye Stephen 2016 IEEE International Conference on Automation, Quality and Testing, Robotics (AQTR) : THETA 20th edition : 19th-21st May, Cluj-Napoca, Romania : proceedings 2016 / [6] p. : ill
<http://dx.doi.org/10.1109/AQTR.2016.7501287>

Multiple fault testing in systems-on-chip with high-level decision diagrams

Ubar, Raimund-Johannes; Oyeniran, Adeboye Stephen; Schölzel, Mario; Vierhaus, Heinrich Theodor Proceedings of 2015 10th International Design & Test Symposium (IDT) : Dead Sea, Jordan, 14-16 December 2015 2015 / p. 66-71 : ill
<http://dx.doi.org/10.1109/IDT.2015.7396738>

Mutation-based verification and error correction in high-level designs = Mutatsioonidel põhinev verifitseerimine ja vigade parandamine kõrgtaseme skeemides

Hantson, Hanno 2015 https://www.ester.ee/record=b4518212*est

Muuk - esimesed triibulised

Tammemäe, Kalle Mente et Manu 2014 / lk. 7-9 : ill https://artiklid.elnet.ee/record=b2679161*est

Nanoelectronics aging mitigation using SSBDD based techniques and dedicated sensors

Ubar, Raimund-Johannes; Vargas, Fabian; Jenihhin, Maksim; Raik, Jaan MEDIAN Workshop on Circuit Reliability : Modeling and Monitoring, Rome, Italy, February 25, 2013 2013 / [1] p

New built-in self-test scheme for SoC interconnect

Jutman, Artur; Ubar, Raimund-Johannes; Raik, Jaan The 9th World Multi-Conference on Systemics, Cybernetics and Informatics : WMSCI 2005 : July 10-13, 2005, Orlando, Florida, USA. Vol. IV 2005 / p. 19-24 : ill
https://www.researchgate.net/publication/237375234_New_Built-In_Self-Test_Scheme_for_SoC_Interconnect

New fault models and self-test generation for microprocessors using High-Level Decision Diagrams

Jasnetski, Artjom; Raik, Jaan; Tšertov, Anton; Ubar, Raimund-Johannes 2015 IEEE 18th International Symposium on Design and Diagnostics of Electronic Circuits & Systems DDECS 2015 : 22-24 April 2015, Belgrade, Serbia : proceedings 2015 / p. 251-254 : ill

New generations of Estonian eGovernment components

Kalja, Ahto; Robal, Tarmo; Vallner, Uno PICMET '15 : proceedings : Management of the Technology Age 2015 / p. 625-631 : ill <http://dx.doi.org/10.1109/PICMET.2015.7273002>

New generations of Estonian eGovernment components

Kalja, Ahto; Robal, Tarmo; Vallner, Uno PICMET '15 Conference : Management of the Technology Age : August 2-6, 2015, Portland, Oregon, USA : conference bulletin 2015 / p. 93

A new measure for calculating multiple fault coverage of microprocessor self-test

Oyeniran, Adeboye Stephen; Odozi, Uzochukwu Eddie; Ubar, Raimund-Johannes BEC 2016 : 2016 15th Biennial Baltic Electronics Conference : proceedings of the 15th Biennial Baltic Electronics Conference : Tallinn University of Technology, October 3-5, 2016, Tallinn, Estonia 2016 / p. 75-78 : ill http://www.ester.ee/record=b2150914*est

NOC mapping and scheduling

Nikiforov, Deniss Info- ja kommunikatsioonitehnoloogia doktorikooli IKTDK seitsmenda aastakonverentsi artiklite kogumik : 15.-16. novembril 2013, Haapsalu 2013 / p. 73-78 : ill

NoCDepend : a flexible and scalable dependability technique for 3D networks-on-chip

Hollstein, Thomas; Azad, Siavoosh Payandeh; Kogge, Thilo; Ying, Haoyuan; Hofmann, Klaus 2015 IEEE 18th International Symposium on Design and Diagnostics of Electronic Circuits & Systems DDECS 2015 : 22-24 April 2015, Belgrade, Serbia : proceedings 2015 / p. 75-78 : ill <http://dx.doi.org/10.1109/DDECS.2015.30>

A novel random approach to diagnostic test generation

Osimiri, Emmanuel Ovie; Ubar, Raimund-Johannes; Kostin, Sergei; Raik, Jaan 2nd IEEE NORCAS Conference : 1-2 November 2016, Copenhagen, Denmark 2016 / [4] p. : ill <https://doi.org/10.1109/NORCHIP.2016.7792915>

Off-line testing of crosstalk induced glitch faults in NoC Interconnects

Bengtsson, Tomas; Kumar, Shashi; **Jutman, Artur; Ubar, Raimund-Johannes** Proceedings [of] 24th IEEE Norchip Conference : Linköping, Sweden, 20-21 November 2006 2006 / p. 221-225 : ill <http://dx.doi.org/10.1109/NORCHIP.2006.329215>

Off-line testing of delay faults in NoC interconnects

Bengtsson, Tomas; **Jutman, Artur;** Kumar, Shashi; Peng, Zebo; **Ubar, Raimund-Johannes** 9th EUROMICRO Conference on Digital Systems Design : Architectures, Methods and Tools (DSD 2006) : 30 August 2006-1 September 2006, Cavtat near Dubrovnik, Croatia : proceedings 2006 / p. 677-680 : ill <http://dx.doi.org/10.1109/DSD.2006.72>

On automatic software-based self-test program generation based on high-Level decision diagrams

Jasnetski, Artjom; Ubar, Raimund-Johannes; Tšertov, Anton LATS 2016 : 17th IEEE Latin-American Test Symposium, Foz do Iguaçu, Brazil, 6th-9th April 2016 2016 / p. 177 <http://dx.doi.org/10.1109/LATW.2016.7483357>

On coverage of timing related faults at board level

Jutman, Artur; Aleksejev, Igor; Devadze, Sergei 2016 21st IEEE European Test Symposium (ETS) : May 23rd-26th 2016, Amsterdam, The Netherlands : proceedings 2016 / [2] p. : ill <https://doi.org/10.1109/ETS.2016.7519295>

On in-system programming of non-volatile memories

Tšertov, Anton; Devadze, Sergei; Jutman, Artur; Jasnetski, Artjom International journal of microelectronics and computer science 2013 / p. 72-78 : ill

On in-system programming of non-volatile memories

Tšertov, Anton; Devadze, Sergei; Jutman, Artur; Jasnetski, Artjom Proceedings of the 20th International Conference Mixed Design of Integrated Circuits and Systems : MIXDES 2013, Gdynia, Poland, June 20-22, 2013 2013 / p. 408-413 : ill

On integration of object-oriented applications with relational databases

Astrova, Irina 2003 http://www.ester.ee/record=b1833107*est

On proving the concept of an ontology aided software refactoring tool

Pöld, Janari; Robal, Tarmo; Kalja, Ahto Databases and information systems VII : selected papers from the tenth International Baltic Conference, DB&IS 2012 2013 / p. 84-94 <https://doi.org/10.3233/978-1-61499-161-8-84> [Article collection metrics at Scopus](#) [Article at Scopus](#) [Article at WOS](#)

On reusability of verification assertions for testing

Jenihhin, Maksim; Raik, Jaan; Ubar, Raimund-Johannes; Tšepurov, Anton BEC 2008 : 2008 International Biennial Baltic Electronics Conference : proceedings of the 11th Biennial Baltic Electronics Conference : Tallinn University of Technology : October 6-8, 2008, Tallinn, Estonia 2008 / p. 151-154 : ill

On using genetic algorithm for test generation

Brik, Marina; Raik, Jaan; Ubar, Raimund-Johannes; Ivask, Eero BEC 2004 : proceedings of the 9th Biennial Baltic Electronics

Conference : October 3-6, 2004, Tallinn, Estonia 2004 / p. 233-236 : ill

On-line fault classification and handling in IEEE1687 based fault management system for complex SoCs

Shibin, Konstantin; Devadze, Sergei; Jutman, Artur LATS 2016 : 17th IEEE Latin-American Test Symposium, Foz do Iguaçu, Brazil, 6th-9th April 2016 2016 / p. 69-74 : ill <https://doi.org/10.1109/LATW.2016.7483342>

On-line monitoring of dialysis adequacy using diaseens optical sensor: accurate Kt/V estimation by smoothing algorithms

Talisainen, Aleksei; Kostin, Sergei; Karai, Deniss; Fridolin, Ivo; Ubar, Raimund-Johannes BEC 2010 : 2010 12th Biennial Baltic Electronics Conference : proceedings of the 12th Biennial Baltic Electronics Conference : Tallinn University of Technology, October 4-6, 2010, Tallinn, Estonia 2010 / p. 273-276 : ill

Ontology-based customization of a scheduling system for discrete manufacturing

Sanko, Jelena; Haav, Hele-Mai; Kotkas, Vahur Databases and information systems IX : selected papers from the twelfth International Baltic Conference, DB&IS 2016 2016 / p. 57-70 : ill <https://doi.org/10.3233/978-1-61499-714-6-57> [Conference Proceedings at Scopus](#) [Article at Scopus](#) [Article at WOS](#)

Open source on-chip logic analyzer for FPGA-s

Ehrenpreis, Lauri; Ellervee, Peeter; Tammemäe, Kalle BEC 2006 : 2006 International Baltic Electronics Conference : Tallinn University of Technology, October 2-4, 2006, Tallinn, Estonia : proceedings of the 10th Biennial Baltic Electronics Conference 2006 / p. 99-102 : ill

Optimization methodologies for Cycle-Accurate SystemC models converted from RTL VHDL

Saif Abrar, Syed; Jenihhin, Maksim; Raik, Jaan IP-SoC 2013 : IP embedded system conference and exhibition : Grenoble, France, November 6-7, 2013 2013

Optimization of address-based data sorting unit with external memory support

Mihhailov, Dmitri; Rjabov, Artjom; Sklyarov, Valery; Skliarova, Iuliia; Sudnitsõn, Aleksander CompSysTech'13 : proceedings of the 14th International Conference on Computer Systems and Technologies 2013 / p. 83-90 : ill <https://doi.org/10.1145/2516775.2516807> [Conference Proceedings at Scopus](#) [Article at Scopus](#)

Optimization of boundary scan tests using FPGA-based efficient scan architectures

Aleksejev, Igor; Devadze, Sergei; Jutman, Artur; Shibin, Konstantin Journal of electronic testing : theory and applications (JETTA) 2016 / p. 245-255 : ill <https://doi.org/10.1007/s10836-016-5588-y> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Optimization of built-in self-test in digital systems = Sisseehitatud enesetestimise optimeerimine digitaalsüsteemides

Kruus, Helena 2011

Optimization of FPGA-based circuits for recursive data sorting

Mihhailov, Dmitri; Sklyarov, Valery; Skliarova, Iuliia; Sudnitsõn, Aleksander BEC 2010 : 2010 12th Biennial Baltic Electronics Conference : proceedings of the 12th Biennial Baltic Electronics Conference : Tallinn University of Technology, October 4-6, 2010, Tallinn, Estonia 2010 / p. 129-132 : ill

Optimization of FSMs network by new encoding strategy

Fomina, Jelena; Sudnitsõn, Aleksander; Vasiliev, Roman BEC 2004 : proceedings of the 9th Biennial Baltic Electronics Conference : October 3-6, 2004, Tallinn, Estonia 2004 / p. 119-122 : ill

Optimization of multisine excitation for a bioimpedance measurement device

Ojarand, Jaan; Annus, Paul; Min, Mart; Gorev, Maksim; Ellervee, Peeter I2MTC 2014 IEEE International Instrumentation and Measurement Technology Conference : Instrumentation and Measurement for Sustainable Development : Radisson Montevideo Victoria Plaza Hotel & Conference Center, May 12-15, 2014, Montevideo, Uruguay : proceedings 2014 / p. 829-832 : ill <https://doi.org/10.1109/I2MTC.2014.6860859> [Conference proceedings at Scopus](#) [Article at Scopus](#) [Article at WOS](#)

Optimization of the store-and-generate based built-in self-test

Ubar, Raimund-Johannes; Jervan, Gert; Kruus, Helena; Orasson, Elmet; Aleksejev, Igor BEC 2006 : 2006 International Baltic Electronics Conference : Tallinn University of Technology, October 2-4, 2006, Tallinn, Estonia : proceedings of the 10th Biennial Baltic Electronics Conference 2006 / p. 199-202 : ill

Otstarbeka, õiglase ja tõhusa Eesti suunas

Ubar, Raimund-Johannes Insenerikultuur Eestis. 2 1995 / lk. 179-185 https://www.ester.ee/record=b1063622*est

Overview about low-level and high-level decision diagrams for diagnostic modeling of digital systems

Ubar, Raimund-Johannes Facta Universitatis [Niš]. Series electronics and energetics 2011 / p. 303-324 : ill <http://dx.doi.org/10.2298/FUEE1103303U>

Perceptions of software development practitioners on client learning

Ojastu, Deniss; Robal, Tarmo; Kalja, Ahto Databases and Information Systems : proceedings of the 11th International Baltic Conference, Baltic DB&IS 2014 : Tallinn, Estonia, 8-11 June, 2014 2014 / p. 397-406

Performance analysis of cosimulating processor core in VHDL and SystemC

Saif Abrar, Syed; Shyam Kiran A.; Jenihhin, Maksim; Raik, Jaan; Babu, C. Proceedings of the 2013 International Conference on Advances in Computing, Communications and Informatics (ICACCI) : 22-25 August 2013, Mysore, India 2013 / p. 563-568 : ill

Pildikesi poolest sajandist : arvutitehnika instituudi lugu

Ubar, Raimund-Johannes 2016 http://www.ester.ee/record=b4639382*est

Pipelined execution of data-parallel algorithms

Gorev, Maksim; Ubar, Raimund-Johannes BEC 2014 : 2014 14th Biennial Baltic Electronics Conference : proceedings of the 14th Biennial Baltic Electronics Conference : Tallinn University of Technology, October 6-8, 2014, Tallinn, Estonia 2014 / p. 109-112 : ill

Polymorphic configuration architecture for CGRAs

Jafri, Syed Mohammad Asad Hassan; Tajammul, Muhammad Adeel; Hermani, Ahmed; Paul, Kolin; Plosila, Juha; Ellervee, Peeter; Tenhunen, Hannu IEEE transactions on Very Large Scale Integration (VLSI) Systems 2016 / p. 403-407 : ill
<http://dx.doi.org/10.1109/TVLSI.2015.2402392>

Practical works for on-line teaching design and test of digital circuits

Jutman, Artur; Ubar, Raimund-Johannes; Hahanov, V.; Skvortsova, O. The 9th IEEE International Conference on Electronics, Circuits and Systems : ICECS 2002 : September 15-18, 2002, Dubrovnik, Croatia. Volume III 2002 / p. 1223-1226 : ill
<http://dx.doi.org/10.1109/ICECS.2002.1046474>

Practicing start-up culture in teaching embedded systems

Reinsalu, Uljana; Azad, Siavoosh Payandeh; Leier, Mairo; Tammemäe, Kalle; Hollstein, Thomas EWME 2016 : 11th European Workshop on Microelectronics Education : May 11-13, 2016, Southampton, UK 2016 / [6] p. : ill
<https://doi.org/10.1109/EWME.2016.7496463>

Preface

Ubar, Raimund-Johannes; Raik, Jaan; Vierhaus, Heinrich Theodor Design and test technology for dependable systems-on-chip 2011 / p. xxii-xxviii

Preface

Haav, Hele-Mai; Kalja, Ahto; Robal, Tarmo Databases and information systems VIII : selected papers from the Eleventh International Baltic Conference, DB&IS 2014 2014 / p. v

Proceedings of the 2012 IEEE 15th International Symposium on Design and Diagnostics of Electronic Circuits & Systems (DDECS) : April 18-20, 2012 Tallinn, Estonia

2012 http://www.ester.ee/record=b2777270*est

Processing N-ary trees in reconfigurable hardware

Sklyarov, Valery; Skliarova, Iouliia; Sudnitsõn, Aleksander 2013 25th International Conference on Microelectronics (ICM) : 15-18 December 2013, Beirut-Lebanon 2013 / p. 13-16 : ill

Processing sorted subsets in a multi-level reconfigurable computing system

Rjabov, Artjom; Sklyarov, Valery; Skliarova, Iouliia; Sudnitsõn, Aleksander Elektronika ir elektrotehnika = Electronics and electrical engineering 2015 / p. 30-33 : ill <https://doi.org/10.5755/j01.eee.21.2.11509> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Professor Andres Keevallik juhib Eesti parima arengudünaamikaga kõrgkooli

Keevallik, Andres; Ehavere, Liis Rapla inimesed 2016 / lk. 146-148 : ill

Professor Raimund Ubari ettekanne [audoktorite promotsioonil TTÜ Nõukogu pidulikul istungil 1. sept. 1993]

Ubar, Raimund-Johannes 75 aastat Tallinna Tehnikaülikooli 1994 / lk. 106-109 https://www.ester.ee/record=b1066846*est

Programmeerimisvõistlus IEEEExtreme 9.0 24h

Tammemäe, Kalle Mente et Manu 2015 / lk. 8-9 : fot https://artiklid.elnet.ee/record=b2750867*est

A proposal for optimisation of low-powered FSM testing

Brik, Marina; Fomina, Jelena; Ubar, Raimund-Johannes Proceedings of IEEE East-West Design & Test Workshop (EWDWTW'05) : Odessa, Ukraine, September 15-19, 2005 2005 / p. 15-20

Pulse wave registration from radial artery using photoplethysmographic method

Pilt, Kristjan; Leier, Mairo; Silluta, Sandra; Kööts, Kristina; Meigas, Kalju; Viigimaa, Margus Conference proceedings : 37th

Rahvusvahelise inseneriorganisatsiooni IEEE Eesti sektsioon sai 10-aastaseks

Tammemäe, Kalle Mente et Manu 2016 / lk. 40-41 : fot http://www.ttu.ee/public/u/ulikool/Tutvustus/ajaleht-mente-et-manu/MM_2016_05/index.html https://artiklid.elnet.ee/record=b2797145*est

Raimund Ubari lühisõnavõtt : riigi teadus-, kultuuri- ja spordipreemiate ning F.J.Wiedemanni keeleauhinna kätteandmisel 24. veebruaril 2016. aastal

Ubar, Raimund-Johannes Raimund-Johannes Ubar. Bibliograafia 2016 / lk. 45-46

Reconfigurable data acquisition unit for bioimpedance measurements

Pesonen, Vadim; Gorev, Maksim; Annus, Paul; Min, Mart; Ellervee, Peeter BEC 2010 : 2010 12th Biennial Baltic Electronics Conference : proceedings of the 12th Biennial Baltic Electronics Conference : Tallinn University of Technology, October 4-6, 2010, Tallinn, Estonia 2010 / p. 257-260 : ill

Refactoring - key to success for constantly developed projects [Electronic resource]

Pöld, Janari; Kalja, Ahto; Robal, Tarmo Proceedings of the 26th International Conference on Information Modelling and Knowledge Bases - EJC 2016 : June 6-10, 2016, Tampere, Finland 2016 / p. 15-24. [USB]

Register-transfer level deductive fault simulation using decision diagrams

Reinsalu, Uljana; Raik, Jaan; Ubar, Raimund-Johannes BEC 2010 : 2010 12th Biennial Baltic Electronics Conference : proceedings of the 12th Biennial Baltic Electronics Conference : Tallinn University of Technology, October 4-6, 2010, Tallinn, Estonia 2010 / p. 193-196 : ill

Rejuvenation of nanoscale logic at NBTI-critical paths using evolutionary TPG

Palermo, N.; **Tihomirov, Valentin**; Copetti, Thiago; **Jenihhin, Maksim; Raik, Jaan; Kostin, Sergei** 2015 16th Latin American Test Symposium (LATS 2015) : Puerto Vallarta, Mexico, 25-27 March 2015 2015 / [6] p. : ill
<http://dx.doi.org/10.1109/LATW.2015.7102405>

Rejuvenation of NBTI-impacted processors using evolutionary generation of assembler programs

Pellerey, Francesco; **Jenihhin, Maksim**; Squillero, Giovanni; **Raik, Jaan**; Sonza Reorda, Matteo; **Tihomirov, Valentin; Ubar, Raimund-Johannes** 2016 IEEE 25th Asian Test Symposium : 21-24 November 2016, Hiroshima, Japan 2016 / p. 304-309 : ill
<https://doi.org/10.1109/ATS.2016.57> [Conference Proceedings at Scopus](#) [Article at Scopus](#) [Article at WOS](#)

Reliability continuum and academic EDA

Jenihhin, Maksim 2nd International Training School on Manufacturable and Dependable Multicore Architectures at Nanoscale (MEDIAN ISTS 2015) : Prague, Czech Republic, July 13-15, 2015 2015 / [1] p

Reliable health monitoring and fault management infrastructure based on embedded instrumentation and IEEE 1687

Jutman, Artur; Shibin, Konstantin; Devadze, Sergei IEEE AUTOTESTCON 2016 : Anaheim, California, USA, September 12-15, 2016 : proceedings 2016 / p. 240-249 : ill <https://doi.org/10.1109/AUTEST.2016.7589605>

Remote and virtual laboratories in problem-based learning scenarios

Wuttke, Heinz-Dietrich; **Ubar, Raimund-Johannes**; Henke, Karsten 2010 IEEE International Symposium on Multimedia ISM 2010 : 13-15 December 2010, Taichung, Taiwan : proceedings 2010 / p. 377-382 : ill <http://dx.doi.org/10.1109/ISM.2010.63>

Requirements-driven model-based testing of the IP Multimedia Subsystem

Ernits, Juhan-Peep; Kääramees, Marko; Raiend, Kullo; Kull, Andres BEC 2008 : 2008 International Biennial Baltic Electronics Conference : proceedings of the 11th Biennial Baltic Electronics Conference : Tallinn University of Technology : October 6-8, 2008, Tallinn, Estonia 2008 / p. 203-206 : ill

Research and training environment for digital design and test

Ubar, Raimund-Johannes; Wuttke, Heinz-Dietrich 34th ASEE/IEEE Frontiers in Education Conference : October 20-23, 2004, Savannah, GA 2004 / p. S3F-18-S3F-23 : ill <http://dx.doi.org/10.1109/FIE.2004.1408779>

Research in digital design and test at Tallinn University of Technology

Ubar, Raimund-Johannes; Jervan, Gert; Jutman, Artur; Raik, Jaan; Ellervee, Peeter; Kruus, Margus Radioelectronics & informatics 2008 / p. 4-12 : ill <http://www.ewdtest.com/ri/%E2%84%96-1-40-january-march-2008/>

Reseeding using compaction of pre-generated LFSR sub-sequences

Jutman, Artur; Alekseev, Igor; Raik, Jaan; Ubar, Raimund-Johannes ICECS 2008 : The 15th IEEE International Conference on Electronics, Circuits and Systems : Malta 2008 / p. 1290-1295 : ill <http://dx.doi.org/10.1109/ICECS.2008.4675096>

Respiration signal extraction from photoplethysmogram using pulse wave amplitude variation

Leier, Mairo; Jervan, Gert; Stork, Wilhelm 2014 IEEE International Conference on Communications (ICC) : Sydney, Australia, June

Riistvara kirjeldamiskeel - VHDL : metoodiline materjal

Tammemäe, Kalle 2003 http://www.ester.ee/record=b1605950*est

Riistvara kirjeldamiskeel VHDL : metoodiline materjal

Tammemäe, Kalle 2002 http://www.ester.ee/record=b1605950*est

Runtime contention and bandwidth-aware adaptive routing selection strategies for networks-on-chip

Samman, Faizal; Hollstein, Thomas; Glesner, Manfred IEEE transactions on parallel and distributed systems 2013 / p. 1411-1421 : ill <https://doi.org/10.1109/TPDS.2012.200> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Run-time reconfigurable instruments for advanced board-level testing

Aleksejev, Igor; Jutman, Artur; Devadze, Sergei IEEE AUTOTESTCON 2016 : Anaheim, California, USA, September 12-15, 2016 : proceedings 2016 / p. 385-392 : ill <https://doi.org/10.1109/AUTEST.2016.7589627>

Scalable algorithm for structural fault collapsing in digital circuits

Ubar, Raimund-Johannes; Jürimägi, Lembit; Orasson, Elmet; Raik, Jaan 2015 IFIP/IEEE International Conference on Very Large Scale Integration (VLSI-Soc) : October 5-7, 2015, Daejeon, Korea 2015 / p. 171-176 : ill

Scalable open platform for reliable medical sensorics = Laiendatav avatud platvorm usaldusväärsete meditsiiniliste sensorite jaoks

Leier, Mairo 2016 https://www.ester.ee/record=b4575148*est

Second IEEE East-West Design and Test Workshop

Hahanov, Vladimir; Ubar, Raimund-Johannes IEEE journal of design & test of computers 2004 / p. 594

Selected issues of modeling, verification and testing of digital systems

Jutman, Artur 2004 https://www.ester.ee/record=b1989760*est

Self-diagnosis in digital systems = Isediagnoosivad digitaalsüsteemid

Kostin, Sergei 2012 https://www.ester.ee/record=b2757857*est

Self-learning tool for digital test

Ubar, Raimund-Johannes; Orasson, Elmet; Evertson, Teet Proceedings of 2nd International Conference "Distance Learning - Educational Sphere of the XXI Century" 2002 / p. 36-38 : ill

Self-testing of pipe-lined signal processing architectures at-speed

Gorev, Maksim; Ubar, Raimund-Johannes; Ellervee, Peeter Info- ja kommunikatsioonitehnoloogia doktorikooli IKTDK seitsmenda aastakonverentsi artiklite kogumik : 15.-16. novembril 2013, Haapsalu 2013 / p. 25-28 : ill

Service quality meter design for self-aware systems

Tammemäe, Kalle; Leier, Mairo AmiES-2015 : Ambient Intelligence and Embedded Systems : International Symposium, 24-26 September, 2015, Oostende, Belgium 2015 / [4] p. : ill

7-valued algebra for transition delay fault analysis

Kõusaar, Jaak; Ubar, Raimund-Johannes BEC 2014 : 2014 14th Biennial Baltic Electronics Conference : proceedings of the 14th Biennial Baltic Electronics Conference : Tallinn University of Technology, October 6-8, 2014, Tallinn, Estonia 2014 / p. 89-92 : ill

Shared Structurally Synthesized BDDs for speeding-up parallel pattern simulation in digital circuits

Ubar, Raimund-Johannes; Jürimägi, Lembit; Raik, Jaan 2015 Nordic Circuits and Systems Conference (NORCAS) : NORCHIP & International Symposium on System-on-Chip (SoC) : 1st IEEE NORCAS Conference : 26-28 October 2015, Oslo, Norway 2015 / [4] p. : ill <http://dx.doi.org/10.1109/NORCHIP.2015.7364406>

Simulation of digital systems with high-level decision diagrams

Morawiec, Adam; Raik, Jaan; Ubar, Raimund-Johannes The 7th Biennial Conference on Electronics and Microsystem Technology "Baltic Electronics Conference" : BEC 2000 : October 8 - 11, 2000, Tallinn, Estonia : conference proceedings 2000 / p. 35-38 : ill

Simulation-based hardware verification with high-level decision diagrams = Simuleerimisel põhinev riistvara verifitseerimine kõrgtaseme otsustusdiagrammidel

Jenihhin, Maksim 2008 https://www.ester.ee/record=b2431332*est

Simulation-based verification with APRICOT framework using high-level decision diagrams

Jenihhin, Maksim; Raik, Jaan; Tšepurov, Anton; Ubar, Raimund-Johannes East-West Design & Test Symposium : Moscow, September 18-21, 2009 2009 / p. 13-16 : ill

Sissejuhatus füüsikasse

Lorents, Peeter 1998 http://www.ester.ee/record=b1207605*est

Sleep apnea pre-screening on neonates and children with shoe integrated sensors [Electronic resource]

Leier, Mairo; Jervan, Gert 31st Norchip Conference : Vilnius, Lithuania, 11-12 November 2013 : conference program and papers 2013 / [4] p. : ill [USB]

A small-size sleep apnea pre-screening prototype for neonates and children

Leier, Mairo; Jervan, Gert Info- ja kommunikatsioonitehnoloogia doktorikooli IKTDK seitsmenda aastakonverentsi artiklite kogumik : 15.-16. novembril 2013, Haapsalu 2013 / p. 49-52 : ill

Smart photoplethysmographic sensor for pulse wave registration at different vascular depths

Leier, Mairo; Jervan, Gert; Pilt, Kristjan Proceedings of the 8th Annual Conference of the Estonian National Doctoral School in Information and Communication Technologies : December 5-6, 2014, Rakvere 2014 / p. 67-70 : ill

Smart photoplethysmographic sensor for pulse wave registration at different vascular depths

Leier, Mairo; Pilt, Kristjan; Karai, Deniss; Jervan, Gert Conference proceedings : 37th Annual International Conference of the IEEE Engineering in Medicine and Biology Society : Milan, Italy, August 25-29 2015 / p. 1849-1852 : ill
<https://doi.org/10.1109/EMBC.2015.7318741> [Conference Proceedings at Scopus](#) [Article at Scopus](#) [Article at WOS](#)

Smart, wireless modular communication platform

Ruberg, Priit; Hollstein, Thomas; Reinsalu, Uljana; Tammemäe, Kalle; Le Moullec, Yannick; Kuusik, Alar; Reidla, Marko; Annus, Paul Proceedings of the 8th Annual Conference of the Estonian National Doctoral School in Information and Communication Technologies : December 5-6, 2014, Rakvere 2014 / p. 111-112 : ill

SoCDep2 : a framework for dependable task deployment on many-core systems under mixed-criticality constraints

Azad, Siavoosh Payandeh; Niazmand, Behrad; Ellervee, Peeter; Raik, Jaan; Jervan, Gert; Hollstein, Thomas 2016 11th International Symposium on Reconfigurable Communication-centric Systems-on-Chip (ReCoSoC) : June 27-29, 2016, Tallinn, Estonia 2016 / [6] p. : ill <https://doi.org/10.1109/ReCoSoC.2016.7533903>

Software-based self-test generation for microprocessors with high-level decision diagrams

Ubar, Raimund-Johannes; Tšertov, Anton; Jasnetski, Artjom; Brik, Marina LATW2014 : 15th IEEE Latin-American Test Workshop : Fortaleza, Brazil, March 12th-15th, 2014 2014 / [6] p. : ill

Software-based self-test generation for microprocessors with high-level decision diagrams

Jasnetski, Artjom; Ubar, Raimund-Johannes; Tšertov, Anton; Brik, Marina Proceedings of the Estonian Academy of Sciences 2014 / p. 48-61 : ill https://artiklid.elnet.ee/record=b2665215*est <https://doi.org/10.3176/proc.2014.1.08> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Solving computationally intensive problems in reconfigurable hardware : a case study

Skliarova, Ioulia; Vallejo, Tiago; Sklyarov, Valery; Sudnitsõn, Aleksander; Kruus, Margus Journal of convergence information technology (JCIT) : an international journal 2013 / p. 601-609 : ill

SPICE-inspired fast gate-level computation of NBTI-induced delays in nanoscale logic

Kostin, Sergei; Raik, Jaan; Ubar, Raimund-Johannes; Jenihhin, Maksim 2015 IEEE 18th International Symposium on Design and Diagnostics of Electronic Circuits & Systems DDECS 2015 : 22-24 April 2015, Belgrade, Serbia : proceedings 2015 / p. 223-228 : ill

SSBDDs : advantageous model and efficient algorithms for digital circuit modeling, simulation & test

Jutman, Artur; Raik, Jaan; Ubar, Raimund-Johannes 5th International Workshop on Boolean Problems : September 19-20, 2002, Freiberg (Sachsen) : proceedings 2002 / p. 157-166 : ill

Structurally synthesized multiple input BDDs for simulation of digital circuits

Ubar, Raimund-Johannes; Mironov, Dmitri; Raik, Jaan; Jutman, Artur 16th IEEE International Conference on Electronics, Circuits, and Systems, ICECS 2009 : Yasmine Hammamet, Tunisia, 13-19 December, 2009 2009 / p. 451-454 : ill
<http://dx.doi.org/10.1109/ICECS.2009.5410895>

A study on effective knowledge reuse in multi-platform web applications user interfaces

Marenkov, Jevgeni; Robal, Tarmo; Kalja, Ahto PICMET '15 Conference : Management of the Technology Age : August 2-6, 2015, Portland, Oregon, USA : conference bulletin 2015 / p. 68

A study on effective knowledge reuse in multi-platform web applications user interfaces

Marenkov, Jevgeni; Robal, Tarmo; Kalja, Ahto PICMET '15 : proceedings : Management of the Technology Age 2015 / p. 1351-1361 : ill <https://doi.org/10.1109/PICMET.2015.7273083>

A study on immediate automatic usability evaluation of web application user interfaces

Marenkov, Jevgeni; Robal, Tarmo; Kalja, Ahto Databases and Information Systems : 12th International Baltic Conference, DB&IS 2016, Riga, Latvia, July 4-6, 2016 : proceedings 2016 / p. 257-271 : ill https://doi.org/10.1007/978-3-319-40180-5_18 [Conference Proceedings at Scopus](#) [Article at Scopus](#) [Article at WOS](#)

A study on user click behaviour for WIS user interface improvements

Marenkov, Jevgeni; Robal, Tarmo; Kalja, Ahto Databases and information systems VIII : selected papers from the Eleventh International Baltic Conference, DB&IS 2014 2014 / p. 173-186 : ill <https://doi.org/10.3233/978-1-61499-458-9-173> [Conference proceedings at Scopus](#) [Article at Scopus](#) [Article at WOS](#)

Studying the incorrect user behaviour in sophisticated self-service portal user interfaces

Marenkov, Jevgeni; Robal, Tarmo; Kalja, Ahto Proceedings of the 8th Annual Conference of the Estonian National Doctoral School in Information and Communication Technologies : December 5-6, 2014, Rakvere 2014 / p. 71-74 : ill

A suite of IEEE 1687 benchmark networks

Tšertov, Anton; Jutman, Artur; Devadze, Sergei 2016 IEEE International Test Conference (ITC) : proceedings 2016 / art. 6.1, p. 1-10 : ill <https://doi.org/10.1109/TEST.2016.7805840>

Süsteemse käsitluse alused : [loengukonspekt]

Lorents, Peeter 2004 http://www.ester.ee/record=b2871388*est

Süsteemse käsitluse alused : riigikaitse ja julgeoleku põhiküsimused

Lorents, Peeter 1998 https://www.ester.ee/record=b1054840*est

Synchronization, calibration and triggering of IEEE 1687 embedded instruments

Jutman, Artur; Devadze, Sergei; Shibin, Konstantin The Seventeenth Workshop on RTL and High Level Testing (WRTL'16) : November 24-25, 2016, Aki Grand Hotel, Hiroshima, Japan 2016 / [6] p

Synthesis of high-level decision diagrams for functional test pattern generation

Ubar, Raimund-Johannes; Raik, Jaan; Karputkin, Anton; Tombak, Mati Proceedings of the 16th International Conference Mixed Design of Integrated Circuits and Systems MIXDES 2009 : Lodz, Poland, 25-27 June, 2009 2009 / p. 519-524 : ill

Synthesis of multiple fault oriented test groups from single fault test sets [Electronic resource]

Ubar, Raimund-Johannes; Kostin, Sergei; Raik, Jaan 2013 8th International Conference on Design & Technology of Integrated Systems in Nanoscale Era (DTIS) : 26-28 March 2013, Abu Dhabi, UAE 2013 / p. 36-41 : ill [CD-ROM]

A synthesis-agnostic behavioral fault model for high gate-level fault coverage

Karputkin, Anton; Raik, Jaan 2016 Design, Automation & Test in Europe Conference & Exhibition (DATE) : proceedings 2016 / p. 1124-1127 : ill <https://ieeexplore.ieee.org/document/7459477/figures#figures>

SysML in systems engineering course

Kruus, Helena; Robal, Tarmo; Jervan, Gert 10th European Workshop on Microelectronics Education : EWME 2014 : May 14-16, 2014, Tallinn, Estonia 2014 / p. 177-181 : ill

A system for teaching basic and advanced topics of IEEE 1149.1 boundary scan standard (extended abstract)

Jutman, Artur; Rosin, Vjatšeslav; Sudnitsõn, Aleksander; Ubar, Raimund-Johannes; Wuttke, Heinz-Dietrich Proceedings of 16th EAEEIE Conference on Innovation in Education for Electrical and Information Engineering (EIE) : Lappeenranta, Finland, 6th-8th June 2005 2005 / [2] p. : ill

System modeling for processor-centric test automation = Süsteemide modelleerimine protsessorikesksete testprogrammide sünteesi automatiseerimiseks

Tšertov, Anton 2012 https://www.ester.ee/record=b2751131*est

SystemC-based loose models : RTL abstraction for design understanding

Abrar, Syed Saif; Jenihhin, Maksim; Raik, Jaan Workshop on Design Automation for Understanding Hardware Designs DUHDe 2015 : Grenoble, March 13, 2015 2015 / p. 1-6

SystemC-based loose models for simulation speed-up by abstraction of RTL IP cores

Abrar, Syed Saif; Jenihhin, Maksim; Raik, Jaan 2015 IEEE 18th International Symposium on Design and Diagnostics of Electronic Circuits & Systems DDECS 2015 : 22-24 April 2015, Belgrade, Serbia : proceedings 2015 / p. 71-74 : ill <http://dx.doi.org/10.1109/DDECS.2015.39>

System-level design of timing-sensitive network-on-chip based dependable systems = Kiipvõrkudel põhinevate ajakriitiliste ja töökindlate süsteemide kõrgtaseme disain

Tagel, Mihkel 2012 https://www.ester.ee/record=b2778263*est

Systems engineering course as a backbone of the computer engineering curricula

Jervan, Gert Proceedings of the 24th International Conference on European Association for Education in Electrical and Information Engineering : 30-31 May 2013, Chania, Greece 2013 / p. 163-166 : ill

zamiaCAD : shall we dance?

Jenihhin, Maksim Open Source Tools for Verification : DVClub 14 January 2013 2013 / 1 p

zamiaCAD : understand, develop and debug hardware designs

Jenihhin, Maksim; Tihomirov, Valentin; Saif Abrar, Syed; Raik, Jaan; Bartsch, Günter DUHDe : 1st Workshop on Design Automation for Understanding Hardware Designs : March 28, 2014 : Friday Workshop at DATE 2014, Dresden, Germany 2014 / p. 1-6

Zynq-based system for extracting sorted subsets from large data sets

Sklyarov, Valery; Skliarova, Ioulia; Rjabov, Artjom; Sudnitsõn, Aleksander Journal of microelectronics, electronic components and materials 2015 / p. 142-152 : ill <https://ojs.midem-drustvo.si/index.php/InfMIDEM/article/view/117/0> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

A task-oriented design of a biologically inspired underwater robot

Listak, Madis 2007 http://www.ester.ee/record=b2298234*est

Teaching advanced test issues in digital electronics

Ubar, Raimund-Johannes; Orasson, Elmet; Raik, Jaan; Wuttke, Heinz-Dietrich Proceedings of the 6th IEEE International Conference on Information Technology Based Higher Education and Training : ITHET : July 7-9, 2005, Juan Dolio, Dominican Republic 2005 / p. S2B-1 - S2B-6 : ill <http://dx.doi.org/10.1109/ITHET.2005.1560318>

Teaching diagnostic modeling of digital systems with decision diagrams [Electronic resource]

Ubar, Raimund-Johannes; Raik, Jaan; Mironov, Dmitri; Evartson, Teet; Orasson, Elmet; Aarna, Margit; Wuttke, Heinz-Dietrich Proceedings of 12th IASTED International Conference on Computers and Advanced Technology in Education - CATE 2009 : St. Thomas, US, November 22-24, 2009 2009 / p. 1-6. [CD-ROM]

Teaching digital RT-level self-test using a Java applet

Devadze, Sergei; Jutman, Artur; Sudnitsõn, Aleksander; Ubar, Raimund-Johannes; Wuttke, Heinz-Dietrich 20th IEEE NORCHIP Conference : Copenhagen, Denmark, November 11-12, 2002 2002 / p. 322-328 : ill

Teaching digital test with BIST analyzer

Jutman, Artur; Tšertov, Anton; Tšepurov, Anton; Aleksejev, Igor; Ubar, Raimund-Johannes; Wuttke, Heinz-Dietrich 19th EAAEE Annual Conference : June 29-July 2, 2008, Tallinn, Estonia : formal proceedings 2008 / p. 123-128 : ill <http://dx.doi.org/10.1109/EAAEE.2008.4610171>

Teaching FPGA-based systems

Skliarova, Ioulia; Sklyarov, Valery; Sudnitsõn, Aleksander; Kruus, Margus 2014 IEEE Global Engineering Education Conference (EDUCON) : Istanbul, Turkey, April 2-5, 2014 2014 / p. 460-469 : ill

Teaching modeling in SysML/UML and problems encountered

Kruus, Helena; Robal, Tarmo; Jervan, Gert Proceedings of the 25th International Conference on European Association for Education in Electrical and Information Engineering : 30 May-June 2014, Cesme, Türkiye 2014 / p. 33-36 : ill

Teaduspreemia laureaadi sõnavõtt : [teaduspreemiate üleandmisel]

Ubar, Raimund-Johannes Eesti Vabariigi preemiad 2016 : teadus. F. J. Wiedemanni keeleaahind. Kultuur. Sport 2016 / lk. 20-21

Teaduspreemia pikaajalise tulemusliku teadus- ja arendustöö eest : Raimund Ubar

Ubar, Raimund-Johannes Eesti Vabariigi preemiad 2016 : teadus. F. J. Wiedemanni keeleaahind. Kultuur. Sport 2016 / lk. 34-61 : fot., portr

Tenniseharrastus Tallinna tehnikaukoolis. Tennis on au sees : [kommenteerivad Tauno Otto ja Viveeth Govind]

Sulling, Andres; Otto, Tauno; Govind, Vineeth Mente et Manu 2013 / lk. 26-27 : fot

10th IEEE European Test Symposium

Ubar, Raimund-Johannes; Prinetto, Paolo; Raik, Jaan IEEE journal of design & test of computers 2005 / p. 480-481 : phot <http://dx.doi.org/10.1109/MDT.2005.106>

Test configurations for diagnosing faulty links in NoC switches

Raik, Jaan; Ubar, Raimund-Johannes; Govind, Vineeth 12th IEEE European Test Symposium ETS 2007 : 20-24 May 2007, Freiburg, Germany : proceedings 2007 / p. 29-34 : ill <http://dx.doi.org/10.1109/ETS.2007.41>

Test development and deployment tool-set for mixed-signal and digital devices

Mellik, Andres; Raik, Jaan BEC 2008 : 2008 International Biennial Baltic Electronics Conference : proceedings of the 11th Biennial Baltic Electronics Conference : Tallinn University of Technology : October 6-8, 2008, Tallinn, Estonia 2008 / p. 163-166 : ill

Testability analysis of digital design verification

Hahanov, V.; Kaminska, M.; **Fomina, Jelena** BEC 2006 : 2006 International Baltic Electronics Conference : Tallinn University of Technology, October 2-4, 2006, Tallinn, Estonia : proceedings of the 10th Biennial Baltic Electronics Conference 2006 / p. 171-174 : ill

The benefits of self-awareness and attention in fog and mist computing

Preden, Jürjo-Sören; Tammemäe, Kalle; Jantsch, Axel; Leier, Mairo; Riid, Andri; Calis, Emine Computer 2015 / p. 37-45 : ill
<https://doi.org/10.1109/MC.2015.207> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

The most prominent software development concepts cited in IT professionals' blogs

Ojastu, Deniss; Robal, Tarmo; Kalja, Ahto Perspectives in business informatics research : 14th International Conference, BIR 2015, Tartu, Estonia, August 26-28, 2015 : proceedings 2015 / p. 197-212 https://doi.org/10.1007/978-3-319-21915-8_13 [Conference proceedings at Scopus](#) [Article at Scopus](#)

The synthesis level in Bloom's taxonomy - a nightmare for an LMS

Wuttke, Heinz-Dietrich; **Ubar, Raimund-Johannes**; Henke, Karsten; **Jutman, Artur** 19th EAAEIE Annual Conference : June 29-July 2, 2008, Tallinn, Estonia : formal proceedings 2008 / p. 199-204 : ill <http://dx.doi.org/10.1109/EAAEIE.2008.4610186>

3D parallel fault simulation

Gorev, Maksim; Ubar, Raimund-Johannes Proceedings of the 8th Annual Conference of the Estonian National Doctoral School in Information and Communication Technologies : December 5-6, 2014, Rakvere 2014 / p. 39-42 : ill

3D routing model in WSN network

Mosidze, Vakhtang Doctoral School in Information and Communication Technology : proceedings of doctoral session of BEC 2014 : October 6-8 2014, Laulasmaa 2014 / p. 11-14 : ill

Throughput estimation with regard to airtime consumption unfairness in mixed data rate Wi-Fi networks

Abdul-Hadi, Alaa Mohammed; Tarasyuk, Olga; Gorbenko, Anatoliy; Kharchenko, Vyacheslav; **Hollstein, Thomas** Communications - Scientific Letters of the University of Žilina 2014 / p. 84-89 : ill <https://komunikacie.uniza.sk/pdfs/csl/2014/01/15.pdf> [Journal metrics at Scopus](#) [Article at Scopus](#)

Tipteadus ja ülikool

Ubar, Raimund-Johannes Mente et Manu 2014 / lk. 11-15 : fot https://artiklid.elnet.ee/record=b2705056*est

Tipteadus ja ülikool

Ubar, Raimund-Johannes Teadusmõte Eestis (VIII). Teaduskultuur : [artiklikogumik] 2013 / lk. 46-53 : portr

A tool for random test generation targeting high diagnostic resolution

Osimiry, Emmanuel Ovie; Kostin, Sergei; Raik, Jaan; Ubar, Raimund-Johannes BEC 2016 : 2016 15th Biennial Baltic Electronics Conference : proceedings of the 15th Biennial Baltic Electronics Conference : Tallinn University of Technology, October 3-5, 2016, Tallinn, Estonia 2016 / p. 79-82 : ill http://www.ester.ee/record=b2150914*est

A tool set for teaching design-for-testability of digital circuits

Kostin, Sergei; Orasson, Elmet; Ubar, Raimund-Johannes EWME 2016 : 11th European Workshop on Microelectronics Education : May 11-13, 2016, Southampton, UK 2016 / [6] p. : ill <https://doi.org/10.1109/EWME.2016.7496466>

Tools and Techniques for event log analysis

Vaarandi, Risto 2005 https://www.ester.ee/record=b2045293*est

Towards adaptive web - analysing and recommending web users' behaviour = Veebikasutajate käitumise analüüs ja soovitusel adaptiivse veebi loomiseks

Robal, Tarmo 2012 https://www.ester.ee/record=b2862251*est

TPI-s kasutatavatest programmidest õppeinfo töötlemisel

Ait, Olev III vabariiklik teaduslik-metoodiline konverents "Õppetöö teaduslik organiseerimine", Kääriku, 24.-25. oktoober 1973. : materjalid 1973 / lk. 128-132 https://www.ester.ee/record=b1324071*est

Transition delay fault simulation with parallel critical path back-tracing and 7-valued algebra

Kõusaar, Jaak; Ubar, Raimund-Johannes; Devadze, Sergei; Raik, Jaan Microprocessors and microsystems 2015 / p. 1130-1138 : ill <https://doi.org/10.1016/j.micpro.2015.05.003> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

TransMem : a memory architecture to support dynamic remapping and parallelism in low power high performance CGRAs

Tajammul, Muhammad Adeel; Jafri, Syed Mohammad Asad Hassan; Hemani, Ahmed; **Ellervee, Peeter** 2016 26th International Workshop on Power and Timing Modeling, Optimization and Simulation : PATMOS 2016 : September, 21st to 23th 2016, Bremen, Germany : proceedings 2016 / p. 92-99 : ill <https://doi.org/10.1109/PATMOS.2016.7833431>

TTBist: a DFT tool for enhancing functional test for SoC

Hermann, K.; **Raik, Jaan; Jenihhin, Maksim** BEC 2006 : 2006 International Baltic Electronics Conference : Tallinn University of Technology, October 2-4, 2006, Tallinn, Estonia : proceedings of the 10th Biennial Baltic Electronics Conference 2006 / p. 191-194 : ill

TTÜ doktorant Mairo Leier: "Ma motiveerin iseennast, tehes seda, mis mulle meeldib."

Leier, Mairo Studioosus 2015 / lk. 8-9 https://www.ester.ee/record=b1558644*est

Ultra fast parallel fault analysis on structurally synthesized BDDs

Ubar, Raimund-Johannes; Devadze, Sergei; Raik, Jaan; Jutman, Artur 12th IEEE European Test Symposium ETS 2007 : 20-24 May 2007, Freiburg, Germany : proceedings 2007 / p. 131-136 : ill <http://dx.doi.org/10.1109/ETS.2007.43>

Untestable fault identification in sequential circuits using model-checking

Raik, Jaan; Fujiwara, Hideo; Ubar, Raimund-Johannes; Krivenko, Anna Proceedings of the 17th Asian Test Symposium ATS 2008 : November 24-27, 2008, Sapporo, Japan 2008 / p. 21-26 : ill <http://dx.doi.org/10.1109/ATS.2008.22>

Using mobile technology to enhance teaching reconfigurable systems

Skliarova, Iuliia; Sklyarov, Valery; **Sudnitsõn, Aleksander; Kruus, Margus** Proceedings of 2013 IEEE International Conference on Teaching, Assessment and Learning for Engineering (TALE) 2013 / p. 478-483 : ill

Using simulation statistics for bug localization in RTL designs

Tihhomirov, Valentin; Jenihhin, Maksim; Raik, Jaan Info- ja kommunikatsioonitehnoloogia doktorikooli IKTDK seitsmenda aastakonverentsi artiklite kogumik : 15.-16. novembril 2013, Haapsalu 2013 / p. 107-110 : ill

Using Tabu Search for optimization of memory-constrained hybrid BIST

Kruus, Helena; Jervan, Gert; Ubar, Raimund-Johannes BEC 2008 : 2008 International Biennial Baltic Electronics Conference : proceedings of the 11th Biennial Baltic Electronics Conference : Tallinn University of Technology : October 6-8, 2008, Tallinn, Estonia 2008 / p. 155-158 : ill

Using weighted graphs for fast architecture exploration

Ellervee, Peeter; Klaar, Tarmo; Kruus, Margus; Tammemäe, Kalle BEC 2002 : proceedings of the 8th Biennial Baltic Electronics Conference : October 6-9, 2002, Tallinn, Estonia 2002 / p. 111-114 : ill

Uurimistoetuse juhend ja vormid

Ubar, Raimund-Johannes 1995 https://www.ester.ee/record=b1067614*est

Variable byte-length data compression algorithm

Gorev, Maksim; Ellervee, Peeter BEC 2010 : 2010 12th Biennial Baltic Electronics Conference : proceedings of the 12th Biennial Baltic Electronics Conference : Tallinn University of Technology, October 4-6, 2010, Tallinn, Estonia 2010 / p. 353-356 : ill

Web-based applet for teaching boundary scan standard IEEE 1149.1

Jutman, Artur; Sudnitsõn, Aleksander; Ubar, Raimund-Johannes Proceedings of the 10th International Conference : Mixed Design of Integrated Circuits and Systems : MIXDES 2003 : Lodz, Poland, 26-28 June 2003 2003 / p. 584-589 : ill
<https://www.semanticscholar.org/paper/WEB-BASED-APPLET-FOR-TEACHING-BOUNDARY-SCAN-IEEE-.-J.-Utman/3bd1b47848612e44772b4c84a2913c419de940fa>

Web-based framework for distributed remote laboratory in the field of digital system test

Ivask, Eero; Jutman, Artur; Raik, Jaan; Ubar, Raimund-Johannes 19th EAEEIE Annual Conference : June 29-July 2, 2008, Tallinn, Estonia : formal proceedings 2008 / p. 182-187 : ill <http://dx.doi.org/10.1109/EAEEIE.2008.4610183>

Web-based software package for e-learning and research training in digital system design

Jutman, Artur; Kruus, Margus; Sudnitsõn, Aleksander; Ubar, Raimund-Johannes; Wuttke, Heinz-Dietrich Информационные технологии в науке, образовании, телекоммуникации и бизнесе : Материалы XXXII Международной конференции IT+SE'2005 : Украина, Крым, Ялта-Гурзуф, 19-28 мая 2005 г 2005 / [2] p

Web-based tools for finite state machine decomposition with analysis of information flows

Fomina, Jelena; Keevallik, Andres; Kruus, Margus; Sudnitsõn, Aleksander BEC 2002 : proceedings of the 8th Biennial Baltic Electronics Conference : October 6-9, 2002, Tallinn, Estonia 2002 / p. 165-168 : ill

Verification and error correction on High-Level Decision Diagrams

Karputkin, Anton 2013

Verification formelle des resultats de la synthese de Haut Niveau : [doktoriväitekirj]

Dušina, Julia 1999

VHDL design debug framework based on zamiaCAD

Tihhomirov, Valentin; Tšepurov, Anton; Saif Abrar, Syed; Jenihhin, Maksim; Raik, Jaan DATE 2013 : Design Automation and Test in Europe, March 18-22, 2013, Grenoble, France 2013 / [1] p. : ill

VHDL front-end for high-level synthesis tool xTractor

Ivask, Eero; Ellervee, Peeter BEC 2004 : proceedings of the 9th Biennial Baltic Electronics Conference : October 3-6, 2004, Tallinn, Estonia 2004 / p. 111-114 : ill

Virtual laboratory for research in dependable microelectronics

Diener, Karl-Heinz; Elst, G.; Gramatova, Elena; Kuzmich, W.; Peng, Z.; **Ubar, Raimund-Johannes** The 7th Biennial Conference on Electronics and Microsystem Technology "Baltic Electronics Conference" : BEC 2000 : October 8 - 11, 2000, Tallinn, Estonia : conference proceedings 2000 / p. 217-220 : ill

Virtual reconfigurable scan-chains on FPGAs for optimized board test

Aleksejev, Igor; Jutman, Artur; Devadze, Sergei; Shubin, Konstantin 2015 16th Latin American Test Symposium (LATS 2015) : Puerto Vallarta, Mexico, 25-27 March 2015 2015 / [6] p. : ill <http://dx.doi.org/10.1109/LATW.2015.7102411>

Ülikooli ülimaks sihiks on teenida oma rahvast : [kõne rektoriks nimetamisel]

Keevallik, Andres Tehnikaülikool 2000 / 20. märts, lk. 6-7 : portr https://www.ester.ee/record=b5309277*est

X-tee on üks infoühiskonna arendusplaani nurgakividest Eestis [Elektrooniline teavik]

Kalja, Ahto Infotehnoloogia avalikus halduses : aastaraamat 2006 2006 / lk. 26-29 https://www.ester.ee/record=b1696552*est

Декомпозиционный синтез управляющих автоматов на программируемых матрицах и микропроцессорах : диссертация на соискание ученой степени кандидата кандидата технических наук

Sudnitsõn, Aleksander 1983 https://www.ester.ee/record=b4634419*est

Построение тестов для неисправностей комбинационных схем на основе анализа ортогональных дизъюнктивных нормальных форм, представляемых альтернативными графами

Matrosova, A.Yu.; Pleshkov, A.G.; **Ubar, Raimund-Johannes** Автоматика и телемеханика 2005 / с. 158-174 : ил <http://mi.mathnet.ru/at1333>

Применение ЭВМ ЕС-1020 при выполнении лабораторных работ по курсу "Физика горных пород. Горное давление"

Kripsaar, Ervin; Zelimhanova, Larissa Опыт применения технических средств в учебном процессе : тезисы докладов VI зональной научно-методической конференции преподавателей вузов республик Прибалтики, БССР и Калининградской области РСФСР 1986 / с. 178-179 https://www.ester.ee/record=b2856606*est

Раймунд Убар: ученые делают свое дело, политики - свое : [интервью с Р. Убаром]

Ubar, Raimund-Johannes Босс : бизнес, организаця, стратегия, системы 2012 / с. 57-58 : ил